

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRR-k encoded:
				5 *
				6 * E651 VCLZDP - VECTOR COUNT LEADING ZERO DIGITS
				7 * E654 VUPKZH - VECTOR UNPACK ZONED HIGH
				8 * E65C VUPKZL - VECTOR UNPACK ZONED LOW
				9 *
				10 * James Wekel June 2024
				11 *****
				12
				13 *****
				14 *
				15 * basic instruction tests
				16 *
				17 *****
				18 * This program tests proper functioning of the z/arch E6 VRR-k vector
				19 * count leading zero digits, unpack zoned high and low instructions.
				20 * Exceptions are not tested.
				21 *
				22 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				23 * obvious coding errors. None of the tests are thorough. They are
				24 * NOT designed to test all aspects of any of the instructions.
				25 *
				26 *****
				27 *
				28 * *Testcase zvector-e6-12-countzonedhighlow: VECTOR E6 VRR-k
				29 * * Zvector E6 tests for VRR-k encoded instruction:
				30 * *
				31 * * E651 VCLZDP - VECTOR COUNT LEADING ZERO DIGITS
				32 * * E654 VUPKZH - VECTOR UNPACK ZONED HIGH
				33 * * E65C VUPKZL - VECTOR UNPACK ZONED LOW
				34 * *
				35 * * # -----
				36 * * # This tests only the basic function of the instruction.
				37 * * # Exceptions are NOT tested.
				38 * * # -----
				39 * *
				40 * main size 2
				41 * numcpu 1
				42 * sysclear
				43 * archlvl z/Arch
				44 * *
				45 * diag8cmd enable # (needed for messages to Hercules console)
				46 * loadcore "\$ (testpath)/zvector-e6-12-countzonedhighlow.core" 0x0
				47 * diag8cmd disable # (reset back to default)
				48 * *
				49 * *Done
				50 *****
00000000	00000000	0000238F	52	ZVE6TST START 0
			53	USING ZVE6TST, R0
			54	
	00000140	00000000	55	SVOLDPSW EQU ZVE6TST+X'140'
				z/Arch Supervisor call old PSW

[illegible]

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						141 *****	
						142 * cc was not as expected	
						143 *****	
00000268	E310	0001	0082	00000268	00000001	144 CCMG EQU *	
0000026E	E310	5007	0076		00000001	145 XG R1, R1	
00000274	5410	8288			00000007	146 LB R1, M3	m3 has CS bit
00000278	4780	804C			00000488	147 N R1, =F' 1'	get CS (CC set) bit
					0000024C	148 BZ TESTREST	ignore if not set
						149 *	
						150 * extract CC extracted PSW	
						151 *	
0000027C	5810	8ED4			000010D4	152 L R1, CCPSW	
00000280	8810	000C			0000000C	153 SRL R1, 12	
00000284	5410	828C			0000048C	154 N R1, =XL4' 3'	
00000288	4210	8EDC			000010DC	155 STC R1, CCFOUND	save cc
						156 *	
						157 * FILL IN MESSAGE	
						158 *	
0000028C	4820	5004			00000004	159 LH R2, TNUM	get test number and convert
00000290	4E20	8EC4			000010C4	160 CVD R2, DECNUM	
00000294	D211	8EAE	8E98	000010AE	00001098	161 MVC PRT3, EDIT	
0000029A	DE11	8EAE	8EC4	000010AE	000010C4	162 ED PRT3, DECNUM	
000002A0	D202	8E53	8EBB	00001053	000010BB	163 MVC CCPRTNUM(3), PRT3+13	fill in message with test #
						164	
000002A6	D207	8E70	500A	00001070	0000000A	165 MVC CCPRTNAME, OPNAME	fill in message with instruction
						166	
000002AC	B982	0022				167 XGR R2, R2	get CC as U8
000002B0	4320	5008			00000008	168 IC R2, CC	
000002B4	4E20	8EC4			000010C4	169 CVD R2, DECNUM	and convert
000002B8	D211	8EAE	8E98	000010AE	00001098	170 MVC PRT3, EDIT	
000002BE	DE11	8EAE	8EC4	000010AE	000010C4	171 ED PRT3, DECNUM	
000002C4	D200	8E86	8EBD	00001086	000010BD	172 MVC CCPRTEXP(1), PRT3+15	fill in message with CC field
						173	
000002CA	B982	0022				174 XGR R2, R2	get CCFOUND as U8
000002CE	4320	8EDC			000010DC	175 IC R2, CCFOUND	
000002D2	4E20	8EC4			000010C4	176 CVD R2, DECNUM	and convert
000002D6	D211	8EAE	8E98	000010AE	00001098	177 MVC PRT3, EDIT	
000002DC	DE11	8EAE	8EC4	000010AE	000010C4	178 ED PRT3, DECNUM	
000002E2	D200	8E96	8EBD	00001096	000010BD	179 MVC CCPRTGOT(1), PRT3+15	fill in message with ccfound
						180	
000002E8	4100	0055			00000055	181 LA R0, CCPRTLNG	message length
000002EC	4110	8E43			00001043	182 LA R1, CCPRTLNE	messagfe address
000002F0	45F0	8160			00000360	183 BAL R15, RPTERROR	
						184	
000002F4	47F0	8142			00000342	185 B FAILCONT	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				187 *****
				188 * result not as expected:
				189 * issue message with test number, instruction under test
				190 * and instruction 12
				191 *****
000002F8	4820 5004	000002F8	00000001	192 FAILMSG EQU *
000002FC	4E20 8EC4		00000004	193 LH R2, TNUM get test number and convert
00000300	D211 8EAE 8E98	000010AE	00001098	194 CVD R2, DECNUM
00000306	DE11 8EAE 8EC4	000010AE	000010C4	195 MWC PRT3, EDIT
0000030C	D202 8E14 8EBB	00001014	000010BB	196 ED PRT3, DECNUM
				197 MWC PRTNUM(3), PRT3+13 fill in message with test #
				198
00000312	D207 8E2F 500A	0000102F	0000000A	199 MWC PRTNAME, OPNAME fill in message with instruction
				200
00000318	B982 0022			201 XGR R2, R2 get M3 as U8
0000031C	4320 5007		00000007	202 IC R2, M3 and convert
00000320	4E20 8EC4		000010C4	203 CVD R2, DECNUM
00000324	D211 8EAE 8E98	000010AE	00001098	204 MWC PRT3, EDIT
0000032A	DE11 8EAE 8EC4	000010AE	000010C4	205 ED PRT3, DECNUM
00000330	D201 8E40 8EBC	00001040	000010BC	206 MWC PRTM3(2), PRT3+14 fill in message with m3 field
				207
00000336	4100 003F		0000003F	208 LA R0, PRTLNG message length
0000033A	4110 8E04		00001004	209 LA R1, PRTLNE messagfe address
0000033E	45F0 8160		00000360	210 BAL R15, RPTERROR
				212 *****
				213 * continue after a failed test
				214 *****
00000342	5800 8288	00000342	00000001	215 FAILCONT EQU *
00000346	5000 8E00		00000488	216 L R0, =F' 1' set GLOBAL failed test indicator
			00001000	217 ST R0, FAILED
				218
0000034A	41C0 C004		00000004	219 LA R12, 4(0, R12) next test address
0000034E	47F0 802A		0000022A	220 B NEXTE6
				222 *****
				223 * end of testing; set ending psw
				224 *****
00000352	5810 8E00	00000352	00000001	225 ENDTEST EQU *
00000356	1211		00001000	226 L R1, FAILED did a test fail?
00000358	4780 8260		00000460	227 LTR R1, R1
0000035C	47F0 8278		00000478	228 BZ EOJ No, exit
				229 B FAILTEST Yes, exit with BAD PSW
				230

[illegible]

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				291 *****
				292 * Normal completion or Abnormal termination PSWs
				293 *****
00000450	00020001 80000000			295 E0JPSW DC OD' 0' , X' 0002000180000000' , AD(0)
00000460	B2B2 8250		00000450	297 E0J LPSWE E0JPSW Normal completion
00000468	00020001 80000000			299 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')
00000478	B2B2 8268		00000468	301 FAILTEST LPSWE FAILPSW Abnormal termination
				303 *****
				304 * Working Storage
				305 *****
0000047C	00000000			307 CTLR0 DS F CRO
00000480	00000000			308 DS F
				309
00000484	000022C8			310 E6TADR DC A(E6TESTS) address of E6 test table
00000488				312 LTORG , Literals pool
00000488	00000001			313 =F' 1'
0000048C	00000003			314 =XL4' 3'
00000490	0000			315 =H' 0'
00000492	005F			316 =AL2(L' MSGMSG)
				317
				318 * some constants
				319
	00000400	00000001		320 K EQU 1024 One KB
	00001000	00000001		321 PAGE EQU (4*K) Size of one page
	00010000	00000001		322 K64 EQU (64*K) 64 KB
	00100000	00000001		323 MB EQU (K*K) 1 MB
				324
				325
	AABBCCDD	00000001		326 REG2PATT EQU X' AABBCCDD' Polluted Register pattern
	000000DD	00000001		327 REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT
					329 *=====
					330 *
					331 * NOTE: start data on an address that is easy to display
					332 * within Hercules
					333 *
					334 *=====
					335
00000494			00000494	00001000	336
00001000	00000000				337 FAILED DC F' 0' some test failed?
					339 *****
					340 * TEST failed : result messgae
					341 *****
					342 *
					343 * failed message and associated editting
					344 *
00001004	40404040	40404040			345 PRTLNE DC C' Test # '
00001014	A7A7A7				346 PRTNUM DC C' xxx'
00001017	40868189	93858440			347 DC C' failed for instruction '
0000102F	A7A7A7A7	A7A7A7A7			348 PRTNAME DC CL8' xxxxxxxx'
00001037	40A689A3	884094F3			349 DC C' with m3='
00001040	A7A7				350 PRTMB DC C' xx'
00001042	4B				351 DC C'.'
			0000003F	00000001	352 PRTLNG EQU *- PRTLNE
					354 *****
					355 * TEST failed : CC message
					356 *****
					357 *
					358 * failed message and associated editting
					359 *
00001043	40404040	40404040			360 CCPRTLNE DC C' Test # '
00001053	A7A7A7				361 CCPRTNUM DC C' xxx'
00001056	40A69996	95874083			362 DC c' wrong cc for instruction '
00001070	A7A7A7A7	A7A7A7A7			363 CCPRTNAME DC CL8' xxxxxxxx'
00001078	4085A797	8583A385			364 DC C' expected: cc='
00001086	A7				365 CCPRTEXP DC C' x'
00001087	6B				366 DC C' ,'
00001088	40998583	8589A585			367 DC C' received: cc='
00001096	A7				368 CCPRTGOT DC C' x'
00001097	4B				369 DC C'.'
			00000055	00000001	370 CCPRTLNG EQU *- CCPRTLNE

[illegible]

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				427 *****
				428 * Macros to help build test tables
				429 *-----
				430 * VRR_K Macro to help build test tables
				431 *****
				432 MACRO
				433 VRR_K &INST, &MB, &CC
				434 . * &INST - instruction under test
				435 . * &MB
				436 . * &CC - expected CC
				437 . *
				438 LCLA &XCC(4) &CC has mask values for FAILED condition codes
				439 &XCC(1) SETA 7 CC != 0
				440 &XCC(2) SETA 11 CC != 1
				441 &XCC(3) SETA 13 CC != 2
				442 &XCC(4) SETA 14 CC != 3
				443
				444 GBLA &TNUM
				445 &TNUM SETA &TNUM+1
				446
				447 DS OFD
				448 USING *, R5 base for test data and test routine
				449
				450 T&TNUM DC A(X&TNUM) address of test routine
				451 DC H' &TNUM test number
				452 DC XL1' 00'
				453 DC HL1' &MB' &MB
				454 DC HL1' &CC' cc
				455 DC HL1' &XCC(&CC+1)' cc failed mask
				456
				457 DC CL8' &INST' instruction name
				458 DC A(16) result length
				459 REA&TNUM DC A(RE&TNUM) result address
				460 . *
				461 * INSTRUCTION UNDER TEST ROUTINE
				462 X&TNUM DS OF
				463 VL V1, V1FUDGE pollute V1
				464 VL V2, RE&TNUM+16 get V2 source
				465
				466 &INST V1, V2, &MB test instruction
				467
				468 VST V1, V10OUTPUT save
				469 EPSW R2, R0 exptract psw
				470 ST R2, CCPSW to save CC
				471
				472 BR R11 return
				473
				474 RE&TNUM DC OF
				475 DROP R5
				476
				477 MEND

479	*****		
480	* PTTABLE Macro to generate table of pointers to individual tests		
481	*****		
482			
483	MACRO		
484	PTTABLE		
485	GBLA	&TNUM	
486	LCLA	&CUR	
487	&CUR	SETA	1
488	. *		
489	TTABLE	DS	OF
490	. LOOP	ANOP	
491	. *		
492		DC	A(T&CUR) address of test
493	. *		
494	&CUR	SETA	&CUR+1
495		AIF	(&CUR LE &TNUM) . LOOP
496	*		
497		DC	A(0) END OF TABLE
498		DC	A(0)
499	. *		
500	MEND		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				502 *****	
				503 * E6 VRR_K tests	
				504 *****	
00001180		00000000	0000238F	505 ZVE6TST CSECT ,	
				506 DS 0F	
				508 PRINT DATA	
				509 *	
				510 * E651 VCLZDP - VECTOR COUNT LEADING ZERO DIGITS	
				511 * E654 VUPKZH - VECTOR UNPACK ZONED HIGH	
				512 * E65C VUPKZL - VECTOR UNPACK ZONED LOW	
				513 *	
				514 * VRR_K instr, m3	
				515 * followed by	
				516 * v1 - expected result (16 bytes)	
				517 * v2 - 16 byte packed decimal source	
				518	
				519 * -----	
				520 * VCLZDP - VECTOR COUNT LEADING ZERO DIGITS	
				521 * -----	
				522 * VCLZDP simple	m3= 1 (NV=0, NZ=0 , CS=1)
				523 *	m3= 3 (NV=0, NZ=1 , CS=1)
				524 *	m3= 5 (NV=1, NZ=0 , CS=1)
				525 *	m3= 7 (NV=1, NZ=1 , CS=1)
00001180				526 VRR_K VCLZDP, 1, 2	
00001180		00001180		527+ DS 0FD	
00001180	0000119C			528+ USING *, R5	base for test data and test routine
00001184	0001			529+T1 DC A(X1)	address of test routine
00001186	00			530+ DC H' 1'	test number
00001187	01			531+ DC XL1' 00'	
00001188	02			532+ DC HL1' 1'	&MB
00001189	0D			533+ DC HL1' 2'	cc
0000118A	E5C3D3E9 C4D74040			534+ DC HL1' 13'	cc failed mask
00001194	00000010			535+ DC CL8' VCLZDP'	instruction name
00001198	000011C0			536+ DC A(16)	result length
				537+REA1 DC A(RE1)	result address
				538+*	INSTRUCTION UNDER TEST ROUTINE
0000119C				539+X1 DS 0F	
0000119C	E710 8F30 0006		00001130	540+ VL V1, V1FUDGE	pollute V1
000011A2	E720 5050 0006		000011D0	541+ VL V2, RE1+16	get V2 source
000011A8	E612 0010 0051			542+ VCLZDP V1, V2, 1	test instruction
000011AE	E710 8EF8 000E		000010F8	543+ VST V1, V10UTPUT	save
000011B4	B98D 0020			544+ EPSW R2, R0	extract psw
000011B8	5020 8ED4		000010D4	545+ ST R2, CCPSW	to save CC
000011BC	07FB			546+ BR R11	return
000011C0				547+RE1 DC 0F	
000011C0				548+ DROP R5	
000011C0	00000000 0000001D			549 DC XL16' 0000000000000001D000000000000000'	V1 result
000011C8	00000000 00000000				
000011D0	00000000 00000000			550 DC XL16' 0000000000000000000000000000000010C'	V2 source
000011D8	00000000 0000010C				
				551	
000011E0				552 VRR_K VCLZDP, 1, 2	
000011E0		000011E0		553+ DS 0FD	
				554+ USING *, R5	base for test data and test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000011E0	000011FC			555+T2	DC	A(X2) address of test routine
000011E4	0002			556+	DC	H' 2' test number
000011E6	00			557+	DC	XL1' 00'
000011E7	01			558+	DC	HL1' 1' &MB
000011E8	02			559+	DC	HL1' 2' cc
000011E9	0D			560+	DC	HL1' 13' cc failed mask
000011EA	E5C3D3E9 C4D74040			561+	DC	CL8' VCLZDP' instruction name
000011F4	00000010			562+	DC	A(16) result length
000011F8	00001220			563+REA2	DC	A(RE2) result address
				564+*		INSTRUCTION UNDER TEST ROUTINE
000011FC				565+X2	DS	0F
000011FC	E710 8F30 0006		00001130	566+	VL	V1, V1FUDGE pollute V1
00001202	E720 9030 0006		00001230	567+	VL	V2, RE2+16 get V2 source
00001208	E612 0010 0051			568+	VCLZDP	V1, V2, 1 test instruction
0000120E	E710 8EF8 000E		000010F8	569+	VST	V1, V10UTPUT save
00001214	B98D 0020			570+	EPSW	R2, R0 exptract psw
00001218	5020 8ED4		000010D4	571+	ST	R2, CCPSW to save CC
0000121C	07FB			572+	BR	R11 return
00001220				573+RE2	DC	0F
00001220				574+	DROP	R5
00001220	00000000 0000000F			575	DC	XL16' 0000000000000000F000000000000000' V1 result
00001228	00000000 00000000					
00001230	00000000 00000001			576	DC	XL16' 00000000000000001110000000000010C' V2 source
00001238	11000000 0000010C					
				577		
				578	VRR_K	VCLZDP, 1, 1
00001240				579+	DS	0FD
00001240		00001240		580+	USING	*, R5 base for test data and test routine
00001240	0000125C			581+T3	DC	A(X3) address of test routine
00001244	0003			582+	DC	H' 3' test number
00001246	00			583+	DC	XL1' 00'
00001247	01			584+	DC	HL1' 1' &MB
00001248	01			585+	DC	HL1' 1' cc
00001249	0B			586+	DC	HL1' 11' cc failed mask
0000124A	E5C3D3E9 C4D74040			587+	DC	CL8' VCLZDP' instruction name
00001254	00000010			588+	DC	A(16) result length
00001258	00001280			589+REA3	DC	A(RE3) result address
				590+*		INSTRUCTION UNDER TEST ROUTINE
0000125C				591+X3	DS	0F
0000125C	E710 8F30 0006		00001130	592+	VL	V1, V1FUDGE pollute V1
00001262	E720 5050 0006		00001290	593+	VL	V2, RE3+16 get V2 source
00001268	E612 0010 0051			594+	VCLZDP	V1, V2, 1 test instruction
0000126E	E710 8EF8 000E		000010F8	595+	VST	V1, V10UTPUT save
00001274	B98D 0020			596+	EPSW	R2, R0 exptract psw
00001278	5020 8ED4		000010D4	597+	ST	R2, CCPSW to save CC
0000127C	07FB			598+	BR	R11 return
00001280				599+RE3	DC	0F
00001280				600+	DROP	R5
00001280	00000000 0000000F			601	DC	XL16' 0000000000000000F000000000000000' V1 result
00001288	00000000 00000000					
00001290	00000000 00000001			602	DC	XL16' 00000000000000001110000000000010D' V2 source
00001298	11000000 0000010D					
				603		
				604	VRR_K	VCLZDP, 1, 0
000012A0				605+	DS	0FD
000012A0		000012A0		606+	USING	*, R5 base for test data and test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000012A0	000012BC			607+T4	DC	A(X4) address of test routine
000012A4	0004			608+	DC	H' 4' test number
000012A6	00			609+	DC	XL1' 00'
000012A7	01			610+	DC	HL1' 1' &MB
000012A8	00			611+	DC	HL1' 0' cc
000012A9	07			612+	DC	HL1' 7' cc failed mask
000012AA	E5C3D3E9 C4D74040			613+	DC	CL8' VCLZDP' instruction name
000012B4	00000010			614+	DC	A(16) result length
000012B8	000012E0			615+REA4	DC	A(RE4) result address
				616+*		INSTRUCTION UNDER TEST ROUTINE
000012BC				617+X4	DS	0F
000012BC	E710 8F30 0006		00001130	618+	VL	V1, V1FUDGE pollute V1
000012C2	E720 5050 0006		000012F0	619+	VL	V2, RE4+16 get V2 source
000012C8	E612 0010 0051			620+	VCLZDP	V1, V2, 1 test instruction
000012CE	E710 8EF8 000E		000010F8	621+	VST	V1, V10UTPUT save
000012D4	B98D 0020			622+	EPSW	R2, R0 exptract psw
000012D8	5020 8ED4		000010D4	623+	ST	R2, CCPSW to save CC
000012DC	07FB			624+	BR	R11 return
000012E0				625+RE4	DC	0F
000012E0				626+	DROP	R5
000012E0	00000000 0000001F			627	DC	XL16' 0000000000000001F000000000000000' V1 result
000012E8	00000000 00000000					
000012F0	00000000 00000000			628	DC	XL16' 00000000000000000000000000000000C' V2 source
000012F8	00000000 0000000C					
				629		
				630	VRR_K	VCLZDP, 1, 0
00001300				631+	DS	0FD
00001300		00001300		632+	USING	*, R5
00001300	0000131C			633+T5	DC	A(X5) base for test data and test routine
00001304	0005			634+	DC	H' 5' address of test routine
00001306	00			635+	DC	XL1' 00' test number
00001307	01			636+	DC	HL1' 1' &MB
00001308	00			637+	DC	HL1' 0' cc
00001309	07			638+	DC	HL1' 7' cc failed mask
0000130A	E5C3D3E9 C4D74040			639+	DC	CL8' VCLZDP' instruction name
00001314	00000010			640+	DC	A(16) result length
00001318	00001340			641+REA5	DC	A(RE5) result address
				642+*		INSTRUCTION UNDER TEST ROUTINE
0000131C				643+X5	DS	0F
0000131C	E710 8F30 0006		00001130	644+	VL	V1, V1FUDGE pollute V1
00001322	E720 5050 0006		00001350	645+	VL	V2, RE5+16 get V2 source
00001328	E612 0010 0051			646+	VCLZDP	V1, V2, 1 test instruction
0000132E	E710 8EF8 000E		000010F8	647+	VST	V1, V10UTPUT save
00001334	B98D 0020			648+	EPSW	R2, R0 exptract psw
00001338	5020 8ED4		000010D4	649+	ST	R2, CCPSW to save CC
0000133C	07FB			650+	BR	R11 return
00001340				651+RE5	DC	0F
00001340				652+	DROP	R5
00001340	00000000 0000001F			653	DC	XL16' 0000000000000001F000000000000000' V1 result
00001348	00000000 00000000					
00001350	00000000 00000000			654	DC	XL16' 00000000000000000000000000000000D' V2 source
00001358	00000000 0000000D					
				655		
				656 * VCLZDP with		m3= 3 (NV=0, NZ=1 , CS=1)
				657		
				658	VRR_K	VCLZDP, 3, 2

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001360				659+	DS	OFD	
00001360		00001360		660+	USING	*, R5	base for test data and test routine
00001360	0000137C			661+T6	DC	A(X6)	address of test routine
00001364	0006			662+	DC	H' 6'	test number
00001366	00			663+	DC	XL1' 00'	
00001367	03			664+	DC	HL1' 3'	&MB
00001368	02			665+	DC	HL1' 2'	cc
00001369	0D			666+	DC	HL1' 13'	cc failed mask
0000136A	E5C3D3E9 C4D74040			667+	DC	CL8' VCLZDP'	instruction name
00001374	00000010			668+	DC	A(16)	result length
00001378	000013A0			669+REA6	DC	A(RE6)	result address
				670+*			INSTRUCTION UNDER TEST ROUTINE
0000137C				671+X6	DS	OF	
0000137C	E710 8F30 0006		00001130	672+	VL	V1, V1FUDGE	pollute V1
00001382	E720 5050 0006		000013B0	673+	VL	V2, RE6+16	get V2 source
00001388	E612 0030 0051			674+	VCLZDP	V1, V2, 3	test instruction
0000138E	E710 8EF8 000E		000010F8	675+	VST	V1, V10UTPUT	save
00001394	B98D 0020			676+	EPSW	R2, R0	exptract psw
00001398	5020 8ED4		000010D4	677+	ST	R2, CCPSW	to save CC
0000139C	07FB			678+	BR	R11	return
000013A0				679+RE6	DC	OF	
000013A0				680+	DROP	R5	
000013A0	00000000 0000001D			681	DC	XL16' 0000000000000001D000000000000000'	V1 result
000013A8	00000000 00000000						
000013B0	00000000 00000000			682	DC	XL16' 0000000000000000000000000000000010C'	V2 source
000013B8	00000000 0000010C						
				683			
				684	VRR_K	VCLZDP, 3, 2	
000013C0				685+	DS	OFD	
000013C0		000013C0		686+	USING	*, R5	base for test data and test routine
000013C0	000013DC			687+T7	DC	A(X7)	address of test routine
000013C4	0007			688+	DC	H' 7'	test number
000013C6	00			689+	DC	XL1' 00'	
000013C7	03			690+	DC	HL1' 3'	&MB
000013C8	02			691+	DC	HL1' 2'	cc
000013C9	0D			692+	DC	HL1' 13'	cc failed mask
000013CA	E5C3D3E9 C4D74040			693+	DC	CL8' VCLZDP'	instruction name
000013D4	00000010			694+	DC	A(16)	result length
000013D8	00001400			695+REA7	DC	A(RE7)	result address
				696+*			INSTRUCTION UNDER TEST ROUTINE
000013DC				697+X7	DS	OF	
000013DC	E710 8F30 0006		00001130	698+	VL	V1, V1FUDGE	pollute V1
000013E2	E720 5050 0006		00001410	699+	VL	V2, RE7+16	get V2 source
000013E8	E612 0030 0051			700+	VCLZDP	V1, V2, 3	test instruction
000013EE	E710 8EF8 000E		000010F8	701+	VST	V1, V10UTPUT	save
000013F4	B98D 0020			702+	EPSW	R2, R0	exptract psw
000013F8	5020 8ED4		000010D4	703+	ST	R2, CCPSW	to save CC
000013FC	07FB			704+	BR	R11	return
00001400				705+RE7	DC	OF	
00001400				706+	DROP	R5	
00001400	00000000 0000000F			707	DC	XL16' 0000000000000000F000000000000000'	V1 result
00001408	00000000 00000000						
00001410	00000000 00000001			708	DC	XL16' 0000000000000000111000000000000010C'	V2 source
00001418	11000000 0000010C						
				709			
				710	VRR_K	VCLZDP, 3, 1	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001420				711+	DS	OFD	
00001420		00001420		712+	USING	*, R5	base for test data and test routine
00001420	0000143C			713+T8	DC	A(X8)	address of test routine
00001424	0008			714+	DC	H' 8'	test number
00001426	00			715+	DC	XL1' 00'	
00001427	03			716+	DC	HL1' 3'	&MB
00001428	01			717+	DC	HL1' 1'	cc
00001429	0B			718+	DC	HL1' 11'	cc failed mask
0000142A	E5C3D3E9 C4D74040			719+	DC	CL8' VCLZDP'	instruction name
00001434	00000010			720+	DC	A(16)	result length
00001438	00001460			721+REA8	DC	A(RE8)	result address
				722+*			INSTRUCTION UNDER TEST ROUTINE
0000143C				723+X8	DS	OF	
0000143C	E710 8F30 0006		00001130	724+	VL	V1, V1FUDGE	pollute V1
00001442	E720 5050 0006		00001470	725+	VL	V2, RE8+16	get V2 source
00001448	E612 0030 0051			726+	VCLZDP	V1, V2, 3	test instruction
0000144E	E710 8EF8 000E		000010F8	727+	VST	V1, V10UTPUT	save
00001454	B98D 0020			728+	EPSW	R2, R0	exptract psw
00001458	5020 8ED4		000010D4	729+	ST	R2, CCPSW	to save CC
0000145C	07FB			730+	BR	R11	return
00001460				731+RE8	DC	OF	
00001460				732+	DROP	R5	
00001460	00000000 0000000F			733	DC	XL16' 0000000000000000F000000000000000'	V1 result
00001468	00000000 00000000						
00001470	00000000 00000001			734	DC	XL16' 00000000000000001110000000000010D'	V2 source
00001478	11000000 0000010D						
				735			
				736	VRR_K	VCLZDP, 3, 0	
00001480				737+	DS	OFD	
00001480		00001480		738+	USING	*, R5	base for test data and test routine
00001480	0000149C			739+T9	DC	A(X9)	address of test routine
00001484	0009			740+	DC	H' 9'	test number
00001486	00			741+	DC	XL1' 00'	
00001487	03			742+	DC	HL1' 3'	&MB
00001488	00			743+	DC	HL1' 0'	cc
00001489	07			744+	DC	HL1' 7'	cc failed mask
0000148A	E5C3D3E9 C4D74040			745+	DC	CL8' VCLZDP'	instruction name
00001494	00000010			746+	DC	A(16)	result length
00001498	000014C0			747+REA9	DC	A(RE9)	result address
				748+*			INSTRUCTION UNDER TEST ROUTINE
0000149C				749+X9	DS	OF	
0000149C	E710 8F30 0006		00001130	750+	VL	V1, V1FUDGE	pollute V1
000014A2	E720 5050 0006		000014D0	751+	VL	V2, RE9+16	get V2 source
000014A8	E612 0030 0051			752+	VCLZDP	V1, V2, 3	test instruction
000014AE	E710 8EF8 000E		000010F8	753+	VST	V1, V10UTPUT	save
000014B4	B98D 0020			754+	EPSW	R2, R0	exptract psw
000014B8	5020 8ED4		000010D4	755+	ST	R2, CCPSW	to save CC
000014BC	07FB			756+	BR	R11	return
000014C0				757+RE9	DC	OF	
000014C0				758+	DROP	R5	
000014C0	00000000 0000001F			759	DC	XL16' 00000000000000001F000000000000000'	V1 result
000014C8	00000000 00000000						
000014D0	00000000 00000000			760	DC	XL16' 000000000000000000000000000000C'	V2 source
000014D8	00000000 0000000C						
				761			
				762	VRR_K	VCLZDP, 3, 1	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000014E0				763+	DS	0FD	
000014E0		000014E0		764+	USING	*,R5	base for test data and test routine
000014E0	000014FC			765+T10	DC	A(X10)	address of test routine
000014E4	000A			766+	DC	H' 10'	test number
000014E6	00			767+	DC	XL1' 00'	
000014E7	03			768+	DC	HL1' 3'	&MB
000014E8	01			769+	DC	HL1' 1'	cc
000014E9	0B			770+	DC	HL1' 11'	cc failed mask
000014EA	E5C3D3E9 C4D74040			771+	DC	CL8' VCLZDP'	instruction name
000014F4	00000010			772+	DC	A(16)	result length
000014F8	00001520			773+REA10	DC	A(RE10)	result address
				774+*			INSTRUCTION UNDER TEST ROUTINE
000014FC				775+X10	DS	0F	
000014FC	E710 8F30 0006		00001130	776+	VL	V1, V1FUDGE	pollute V1
00001502	E720 5050 0006		00001530	777+	VL	V2, RE10+16	get V2 source
00001508	E612 0030 0051			778+	VCLZDP	V1, V2, 3	test instruction
0000150E	E710 8EF8 000E		000010F8	779+	VST	V1, V10UTPUT	save
00001514	B98D 0020			780+	EPSW	R2, R0	exptract psw
00001518	5020 8ED4		000010D4	781+	ST	R2, CCPSW	to save CC
0000151C	07FB			782+	BR	R11	return
00001520				783+RE10	DC	0F	
00001520				784+	DROP	R5	
00001520	00000000 0000001F			785	DC	XL16' 0000000000000001F000000000000000'	V1 result
00001528	00000000 00000000						
00001530	00000000 00000000			786	DC	XL16' 000000000000000000000000000000D'	V2 source
00001538	00000000 0000000D						
				787			
				788 * VCLZDP with			m3= 5 (NV=1, NZ=0 , CS=1)
				789			
				790	VRR_K	VCLZDP, 5, 2	
00001540				791+	DS	0FD	
00001540		00001540		792+	USING	*,R5	base for test data and test routine
00001540	0000155C			793+T11	DC	A(X11)	address of test routine
00001544	000B			794+	DC	H' 11'	test number
00001546	00			795+	DC	XL1' 00'	
00001547	05			796+	DC	HL1' 5'	&MB
00001548	02			797+	DC	HL1' 2'	cc
00001549	0D			798+	DC	HL1' 13'	cc failed mask
0000154A	E5C3D3E9 C4D74040			799+	DC	CL8' VCLZDP'	instruction name
00001554	00000010			800+	DC	A(16)	result length
00001558	00001580			801+REA11	DC	A(RE11)	result address
				802+*			INSTRUCTION UNDER TEST ROUTINE
0000155C				803+X11	DS	0F	
0000155C	E710 8F30 0006		00001130	804+	VL	V1, V1FUDGE	pollute V1
00001562	E720 5050 0006		00001590	805+	VL	V2, RE11+16	get V2 source
00001568	E612 0050 0051			806+	VCLZDP	V1, V2, 5	test instruction
0000156E	E710 8EF8 000E		000010F8	807+	VST	V1, V10UTPUT	save
00001574	B98D 0020			808+	EPSW	R2, R0	exptract psw
00001578	5020 8ED4		000010D4	809+	ST	R2, CCPSW	to save CC
0000157C	07FB			810+	BR	R11	return
00001580				811+RE11	DC	0F	
00001580				812+	DROP	R5	
00001580	00000000 0000001D			813	DC	XL16' 0000000000000001D000000000000000'	V1 result
00001588	00000000 00000000						
00001590	00000000 00000000			814	DC	XL16' 000000000000000000000000000010C'	V2 source
00001598	00000000 0000010C						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				815		
				816	VRR_K	VCLZDP, 5, 2
000015A0				817+	DS	OFD
000015A0		000015A0		818+	USING	*, R5
000015A0	000015BC			819+T12	DC	A(X12)
000015A4	000C			820+	DC	H' 12'
000015A6	00			821+	DC	XL1' 00'
000015A7	05			822+	DC	HL1' 5'
000015A8	02			823+	DC	HL1' 2'
000015A9	0D			824+	DC	HL1' 13'
000015AA	E5C3D3E9 C4D74040			825+	DC	CL8' VCLZDP'
000015B4	00000010			826+	DC	A(16)
000015B8	000015E0			827+REA12	DC	A(RE12)
				828+*		INSTRUCTION UNDER TEST ROUTINE
000015BC				829+X12	DS	OF
000015BC	E710 8F30 0006		00001130	830+	VL	V1, V1FUDGE
000015C2	E720 5050 0006		000015F0	831+	VL	V2, RE12+16
000015C8	E612 0050 0051			832+	VCLZDP	V1, V2, 5
000015CE	E710 8EF8 000E		000010F8	833+	VST	V1, V10OUTPUT
000015D4	B98D 0020			834+	EPSW	R2, R0
000015D8	5020 8ED4		000010D4	835+	ST	R2, CCPSW
000015DC	07FB			836+	BR	R11
000015E0				837+RE12	DC	OF
000015E0				838+	DROP	R5
000015E0	00000000 0000000F			839	DC	XL16' 0000000000000000F000000000000000' V1 result
000015E8	00000000 00000000					
000015F0	00000000 00000001			840	DC	XL16' 00000000000000001110000000000010C' V2 source
000015F8	11000000 0000010C					
				841		
				842	VRR_K	VCLZDP, 5, 1
00001600				843+	DS	OFD
00001600		00001600		844+	USING	*, R5
00001600	0000161C			845+T13	DC	A(X13)
00001604	000D			846+	DC	H' 13'
00001606	00			847+	DC	XL1' 00'
00001607	05			848+	DC	HL1' 5'
00001608	01			849+	DC	HL1' 1'
00001609	0B			850+	DC	HL1' 11'
0000160A	E5C3D3E9 C4D74040			851+	DC	CL8' VCLZDP'
00001614	00000010			852+	DC	A(16)
00001618	00001640			853+REA13	DC	A(RE13)
				854+*		INSTRUCTION UNDER TEST ROUTINE
0000161C				855+X13	DS	OF
0000161C	E710 8F30 0006		00001130	856+	VL	V1, V1FUDGE
00001622	E720 5050 0006		00001650	857+	VL	V2, RE13+16
00001628	E612 0050 0051			858+	VCLZDP	V1, V2, 5
0000162E	E710 8EF8 000E		000010F8	859+	VST	V1, V10OUTPUT
00001634	B98D 0020			860+	EPSW	R2, R0
00001638	5020 8ED4		000010D4	861+	ST	R2, CCPSW
0000163C	07FB			862+	BR	R11
00001640				863+RE13	DC	OF
00001640				864+	DROP	R5
00001640	00000000 0000000F			865	DC	XL16' 0000000000000000F000000000000000' V1 result
00001648	00000000 00000000					
00001650	00000000 00000001			866	DC	XL16' 00000000000000001110000000000010D' V2 source
00001658	11000000 0000010D					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				867		
				868	VRR_K	VCLZDP, 5, 0
00001660				869+	DS	OFD
00001660		00001660		870+	USING	*, R5
00001660	0000167C			871+T14	DC	A(X14)
00001664	000E			872+	DC	H' 14'
00001666	00			873+	DC	XL1' 00'
00001667	05			874+	DC	HL1' 5'
00001668	00			875+	DC	HL1' 0'
00001669	07			876+	DC	HL1' 7'
0000166A	E5C3D3E9 C4D74040			877+	DC	CL8' VCLZDP'
00001674	00000010			878+	DC	A(16)
00001678	000016A0			879+REA14	DC	A(RE14)
				880+*		INSTRUCTION UNDER TEST ROUTINE
0000167C				881+X14	DS	OF
0000167C	E710 8F30 0006		00001130	882+	VL	V1, V1FUDGE
00001682	E720 5050 0006		000016B0	883+	VL	V2, RE14+16
00001688	E612 0050 0051			884+	VCLZDP	V1, V2, 5
0000168E	E710 8EF8 000E		000010F8	885+	VST	V1, V10OUTPUT
00001694	B98D 0020			886+	EPSW	R2, R0
00001698	5020 8ED4		000010D4	887+	ST	R2, CCPSW
0000169C	07FB			888+	BR	R11
000016A0				889+RE14	DC	OF
000016A0				890+	DROP	R5
000016A0	00000000 0000001F			891	DC	XL16' 0000000000000001F000000000000000' V1 result
000016A8	00000000 00000000					
000016B0	00000000 00000000			892	DC	XL16' 000000000000000000000000000000C' V2 source
000016B8	00000000 0000000C					
				893		
				894	VRR_K	VCLZDP, 5, 0
000016C0				895+	DS	OFD
000016C0		000016C0		896+	USING	*, R5
000016C0	000016DC			897+T15	DC	A(X15)
000016C4	000F			898+	DC	H' 15'
000016C6	00			899+	DC	XL1' 00'
000016C7	05			900+	DC	HL1' 5'
000016C8	00			901+	DC	HL1' 0'
000016C9	07			902+	DC	HL1' 7'
000016CA	E5C3D3E9 C4D74040			903+	DC	CL8' VCLZDP'
000016D4	00000010			904+	DC	A(16)
000016D8	00001700			905+REA15	DC	A(RE15)
				906+*		INSTRUCTION UNDER TEST ROUTINE
000016DC				907+X15	DS	OF
000016DC	E710 8F30 0006		00001130	908+	VL	V1, V1FUDGE
000016E2	E720 5050 0006		00001710	909+	VL	V2, RE15+16
000016E8	E612 0050 0051			910+	VCLZDP	V1, V2, 5
000016EE	E710 8EF8 000E		000010F8	911+	VST	V1, V10OUTPUT
000016F4	B98D 0020			912+	EPSW	R2, R0
000016F8	5020 8ED4		000010D4	913+	ST	R2, CCPSW
000016FC	07FB			914+	BR	R11
00001700				915+RE15	DC	OF
00001700				916+	DROP	R5
00001700	00000000 0000001F			917	DC	XL16' 0000000000000001F000000000000000' V1 result
00001708	00000000 00000000					
00001710	00000000 00000000			918	DC	XL16' 00000000000000000000000000000D' V2 source
00001718	00000000 0000000D					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				919		
				920	VRR_K VCLZDP, 5, 3	
00001720				921+	DS OFD	
00001720		00001720		922+	USING *, R5	base for test data and test routine
00001720	0000173C			923+T16	DC A(X16)	address of test routine
00001724	0010			924+	DC H' 16'	test number
00001726	00			925+	DC XL1' 00'	
00001727	05			926+	DC HL1' 5'	&MB
00001728	03			927+	DC HL1' 3'	cc
00001729	0E			928+	DC HL1' 14'	cc failed mask
0000172A	E5C3D3E9 C4D74040			929+	DC CL8' VCLZDP'	instruction name
00001734	00000010			930+	DC A(16)	result length
00001738	00001760			931+REA16	DC A(RE16)	result address
				932+*		INSTRUCTION UNDER TEST ROUTINE
0000173C				933+X16	DS OF	
0000173C	E710 8F30 0006		00001130	934+	VL V1, V1FUDGE	pollute V1
00001742	E720 5050 0006		00001770	935+	VL V2, RE16+16	get V2 source
00001748	E612 0050 0051			936+	VCLZDP V1, V2, 5	test instruction
0000174E	E710 8EF8 000E		000010F8	937+	VST V1, V10OUTPUT	save
00001754	B98D 0020			938+	EPSW R2, R0	extract psw
00001758	5020 8ED4		000010D4	939+	ST R2, CCPSW	to save CC
0000175C	07FB			940+	BR R11	return
00001760				941+RE16	DC OF	
00001760				942+	DROP R5	
00001760	00000000 00000002			943	DC XL16' 00000000000000002000000000000000'	V1 result
00001768	00000000 00000000					
00001770	00AAA000 00000000			944	DC XL16' 00AAA00000000000000000000000000D'	V2 source
00001778	00000000 0000000D					
				945		
				946 * VCLZDP with		m3= 7 (NV=1, NZ=1 , CS=1)
				947		
				948	VRR_K VCLZDP, 7, 2	
00001780				949+	DS OFD	
00001780		00001780		950+	USING *, R5	base for test data and test routine
00001780	0000179C			951+T17	DC A(X17)	address of test routine
00001784	0011			952+	DC H' 17'	test number
00001786	00			953+	DC XL1' 00'	
00001787	07			954+	DC HL1' 7'	&MB
00001788	02			955+	DC HL1' 2'	cc
00001789	0D			956+	DC HL1' 13'	cc failed mask
0000178A	E5C3D3E9 C4D74040			957+	DC CL8' VCLZDP'	instruction name
00001794	00000010			958+	DC A(16)	result length
00001798	000017C0			959+REA17	DC A(RE17)	result address
				960+*		INSTRUCTION UNDER TEST ROUTINE
0000179C				961+X17	DS OF	
0000179C	E710 8F30 0006		00001130	962+	VL V1, V1FUDGE	pollute V1
000017A2	E720 5050 0006		000017D0	963+	VL V2, RE17+16	get V2 source
000017A8	E612 0070 0051			964+	VCLZDP V1, V2, 7	test instruction
000017AE	E710 8EF8 000E		000010F8	965+	VST V1, V10OUTPUT	save
000017B4	B98D 0020			966+	EPSW R2, R0	extract psw
000017B8	5020 8ED4		000010D4	967+	ST R2, CCPSW	to save CC
000017BC	07FB			968+	BR R11	return
000017C0				969+RE17	DC OF	
000017C0				970+	DROP R5	
000017C0	00000000 0000001D			971	DC XL16' 00000000000000001D000000000000000'	V1 result
000017C8	00000000 00000000					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000017D0	00000000 00000000			972	DC	XL16' 0000000000000000000000000000000010C' V2 source
000017D8	00000000 0000010C					
				973		
				974	VRR_K	VCLZDP, 7, 2
000017E0				975+	DS	OFD
000017E0		000017E0		976+	USING	*, R5
000017E0	000017FC			977+T18	DC	A(X18)
000017E4	0012			978+	DC	H' 18'
000017E6	00			979+	DC	XL1' 00'
000017E7	07			980+	DC	HL1' 7'
000017E8	02			981+	DC	HL1' 2'
000017E9	0D			982+	DC	HL1' 13'
000017EA	E5C3D3E9 C4D74040			983+	DC	CL8' VCLZDP'
000017F4	00000010			984+	DC	A(16)
000017F8	00001820			985+REA18	DC	A(RE18)
				986+*		INSTRUCTION UNDER TEST ROUTINE
000017FC				987+X18	DS	OF
000017FC	E710 8F30 0006		00001130	988+	VL	V1, V1FUDGE
00001802	E720 5050 0006		00001830	989+	VL	V2, RE18+16
00001808	E612 0070 0051			990+	VCLZDP	V1, V2, 7
0000180E	E710 8EF8 000E		000010F8	991+	VST	V1, V10UTPUT
00001814	B98D 0020			992+	EPSW	R2, R0
00001818	5020 8ED4		000010D4	993+	ST	R2, CCPSW
0000181C	07FB			994+	BR	R11
00001820				995+RE18	DC	OF
00001820				996+	DROP	R5
00001820	00000000 0000000F			997	DC	XL16' 0000000000000000F000000000000000' V1 result
00001828	00000000 00000000					
00001830	00000000 00000001			998	DC	XL16' 00000000000000001110000000000010C' V2 source
00001838	11000000 0000010C					
				999		
				1000	VRR_K	VCLZDP, 7, 1
00001840				1001+	DS	OFD
00001840		00001840		1002+	USING	*, R5
00001840	0000185C			1003+T19	DC	A(X19)
00001844	0013			1004+	DC	H' 19'
00001846	00			1005+	DC	XL1' 00'
00001847	07			1006+	DC	HL1' 7'
00001848	01			1007+	DC	HL1' 1'
00001849	0B			1008+	DC	HL1' 11'
0000184A	E5C3D3E9 C4D74040			1009+	DC	CL8' VCLZDP'
00001854	00000010			1010+	DC	A(16)
00001858	00001880			1011+REA19	DC	A(RE19)
				1012+*		INSTRUCTION UNDER TEST ROUTINE
0000185C				1013+X19	DS	OF
0000185C	E710 8F30 0006		00001130	1014+	VL	V1, V1FUDGE
00001862	E720 5050 0006		00001890	1015+	VL	V2, RE19+16
00001868	E612 0070 0051			1016+	VCLZDP	V1, V2, 7
0000186E	E710 8EF8 000E		000010F8	1017+	VST	V1, V10UTPUT
00001874	B98D 0020			1018+	EPSW	R2, R0
00001878	5020 8ED4		000010D4	1019+	ST	R2, CCPSW
0000187C	07FB			1020+	BR	R11
00001880				1021+RE19	DC	OF
00001880				1022+	DROP	R5
00001880	00000000 0000000F			1023	DC	XL16' 0000000000000000F000000000000000' V1 result
00001888	00000000 00000000					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001890	00000000 00000001			1024	DC	XL16' 00000000000000001110000000000010D' V2 source
00001898	11000000 0000010D					
				1025		
				1026	VRR_K	VCLZDP, 7, 0
000018A0				1027+	DS	OFD
000018A0		000018A0		1028+	USING	*, R5
000018A0	000018BC			1029+T20	DC	A(X20)
000018A4	0014			1030+	DC	H' 20'
000018A6	00			1031+	DC	XL1' 00'
000018A7	07			1032+	DC	HL1' 7'
000018A8	00			1033+	DC	HL1' 0'
000018A9	07			1034+	DC	HL1' 7'
000018AA	E5C3D3E9 C4D74040			1035+	DC	CL8' VCLZDP'
000018B4	00000010			1036+	DC	A(16)
000018B8	000018E0			1037+REA20	DC	A(RE20)
				1038+*		INSTRUCTION UNDER TEST ROUTINE
000018BC				1039+X20	DS	OF
000018BC	E710 8F30 0006		00001130	1040+	VL	V1, V1FUDGE
000018C2	E720 5050 0006		000018F0	1041+	VL	V2, RE20+16
000018C8	E612 0070 0051			1042+	VCLZDP	V1, V2, 7
000018CE	E710 8EF8 000E		000010F8	1043+	VST	V1, V10UTPUT
000018D4	B98D 0020			1044+	EPSW	R2, R0
000018D8	5020 8ED4		000010D4	1045+	ST	R2, CCPSW
000018DC	07FB			1046+	BR	R11
000018E0				1047+RE20	DC	OF
000018E0				1048+	DROP	R5
000018E0	00000000 0000001F			1049	DC	XL16' 00000000000000001F0000000000000000' V1 result
000018E8	00000000 00000000					
000018F0	00000000 00000000			1050	DC	XL16' 00000000000000000000000000000000C' V2 source
000018F8	00000000 0000000C					
				1051		
				1052	VRR_K	VCLZDP, 7, 1
00001900				1053+	DS	OFD
00001900		00001900		1054+	USING	*, R5
00001900	0000191C			1055+T21	DC	A(X21)
00001904	0015			1056+	DC	H' 21'
00001906	00			1057+	DC	XL1' 00'
00001907	07			1058+	DC	HL1' 7'
00001908	01			1059+	DC	HL1' 1'
00001909	0B			1060+	DC	HL1' 11'
0000190A	E5C3D3E9 C4D74040			1061+	DC	CL8' VCLZDP'
00001914	00000010			1062+	DC	A(16)
00001918	00001940			1063+REA21	DC	A(RE21)
				1064+*		INSTRUCTION UNDER TEST ROUTINE
0000191C				1065+X21	DS	OF
0000191C	E710 8F30 0006		00001130	1066+	VL	V1, V1FUDGE
00001922	E720 5050 0006		00001950	1067+	VL	V2, RE21+16
00001928	E612 0070 0051			1068+	VCLZDP	V1, V2, 7
0000192E	E710 8EF8 000E		000010F8	1069+	VST	V1, V10UTPUT
00001934	B98D 0020			1070+	EPSW	R2, R0
00001938	5020 8ED4		000010D4	1071+	ST	R2, CCPSW
0000193C	07FB			1072+	BR	R11
00001940				1073+RE21	DC	OF
00001940				1074+	DROP	R5
00001940	00000000 0000001F			1075	DC	XL16' 00000000000000001F0000000000000000' V1 result
00001948	00000000 00000000					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001950	00000000 00000000			1076	DC	XL16' 000000000000000000000000000000D' V2 source
00001958	00000000 0000000D					
				1077		
				1078	VRR_K	VCLZDP, 7, 3
00001960				1079+	DS	OFD
00001960		00001960		1080+	USING	*, R5
00001960	0000197C			1081+T22	DC	A(X22)
00001964	0016			1082+	DC	H' 22'
00001966	00			1083+	DC	XL1' 00'
00001967	07			1084+	DC	HL1' 7'
00001968	03			1085+	DC	HL1' 3'
00001969	0E			1086+	DC	HL1' 14'
0000196A	E5C3D3E9 C4D74040			1087+	DC	CL8' VCLZDP'
00001974	00000010			1088+	DC	A(16)
00001978	000019A0			1089+REA22	DC	A(RE22)
				1090+*		INSTRUCTION UNDER TEST ROUTINE
0000197C				1091+X22	DS	OF
0000197C	E710 8F30 0006		00001130	1092+	VL	V1, V1FUDGE
00001982	E720 5050 0006		000019B0	1093+	VL	V2, RE22+16
00001988	E612 0070 0051			1094+	VCLZDP	V1, V2, 7
0000198E	E710 8EF8 000E		000010F8	1095+	VST	V1, V10UTPUT
00001994	B98D 0020			1096+	EPSW	R2, R0
00001998	5020 8ED4		000010D4	1097+	ST	R2, CCPSW
0000199C	07FB			1098+	BR	R11
000019A0				1099+RE22	DC	OF
000019A0				1100+	DROP	R5
000019A0	00000000 00000002			1101	DC	XL16' 00000000000000020000000000000000' V1 result
000019A8	00000000 00000000					
000019B0	00AAA000 00000000			1102	DC	XL16' 00AAA0000000000000000000000000D' V2 source
000019B8	00000000 0000000D					
				1103		
				1104	*	-----
				1105	*	VUPKZH - VECTOR UNPACK ZONED HIGH
				1106	*	-----
				1107	*	NOTE NOTE: VUPKZH does NOT set the condition code!
				1108	*	m3 bit 3 should be ZERO (which matches the CS bit of VCLZDP
				1109	*	so CC checking should be skipped!!)
				1110	*	-----
				1111	*	VUPKZH simple
				1112	*	m3= 0 (NSV=0, NV=0 , fake CS=0)
				1113	*	m3= 4 (NSV=0, NV=1 , fake CS=0)
				1114	*	m3= 8 (NSV=1, NV=0 , fake CS=0)
				1115	*	m3= 12 (NSV=1, NV=1 , fake CS=0)
				1116	VRR_K	VUPKZH, 0, 0
000019C0				1117+	DS	OFD
000019C0		000019C0		1118+T23	USING	*, R5
000019C0	000019DC			1119+	DC	A(X23)
000019C4	0017			1120+	DC	H' 23'
000019C6	00			1121+	DC	XL1' 00'
000019C7	00			1122+	DC	HL1' 0'
000019C8	00			1123+	DC	HL1' 0'
000019C9	07			1124+	DC	HL1' 7'
000019CA	E5E4D7D2 E9C84040			1125+	DC	CL8' VUPKZH'
000019D4	00000010			1126+REA23	DC	A(RE23)
000019D8	00001A00			1127+*		INSTRUCTION UNDER TEST ROUTINE
000019DC				1128+X23	DS	OF

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000019DC	E710 8F30 0006		00001130	1129+	VL	V1, V1FUDGE	pollute V1
000019E2	E720 5050 0006		00001A10	1130+	VL	V2, RE23+16	get V2 source
000019E8	E612 0000 0054			1131+	VUPKZH	V1, V2, 0	test instruction
000019EE	E710 8EF8 000E		000010F8	1132+	VST	V1, V10UTPUT	save
000019F4	B98D 0020			1133+	EPSW	R2, R0	exptract psw
000019F8	5020 8ED4		000010D4	1134+	ST	R2, CCPSW	to save CC
000019FC	07FB			1135+	BR	R11	return
00001A00				1136+RE23	DC	0F	
00001A00				1137+	DROP	R5	
00001A00	F0F1F2F3 F4F5F6F7			1138	DC	XL16' F0F1F2F3F4F5F6F7F8F9F0F1F2F3F4F5'	V1 result
00001A08	F8F9F0F1 F2F3F4F5						
00001A10	12345678 90123456			1139	DC	XL16' 1234567890123456789012345678901C'	V2 source
00001A18	78901234 5678901C						
				1140			
				1141	VRR_K	VUPKZH, 0, 0	
00001A20				1142+	DS	0FD	
00001A20		00001A20		1143+	USING	*, R5	base for test data and test routine
00001A20	00001A3C			1144+T24	DC	A(X24)	address of test routine
00001A24	0018			1145+	DC	H' 24'	test number
00001A26	00			1146+	DC	XL1' 00'	
00001A27	00			1147+	DC	HL1' 0'	&MB
00001A28	00			1148+	DC	HL1' 0'	cc
00001A29	07			1149+	DC	HL1' 7'	cc failed mask
00001A2A	E5E4D7D2 E9C84040			1150+	DC	CL8' VUPKZH'	instruction name
00001A34	00000010			1151+	DC	A(16)	result length
00001A38	00001A60			1152+REA24	DC	A(RE24)	result address
				1153+*			INSTRUCTION UNDER TEST ROUTINE
00001A3C				1154+X24	DS	0F	
00001A3C	E710 8F30 0006		00001130	1155+	VL	V1, V1FUDGE	pollute V1
00001A42	E720 5050 0006		00001A70	1156+	VL	V2, RE24+16	get V2 source
00001A48	E612 0000 0054			1157+	VUPKZH	V1, V2, 0	test instruction
00001A4E	E710 8EF8 000E		000010F8	1158+	VST	V1, V10UTPUT	save
00001A54	B98D 0020			1159+	EPSW	R2, R0	exptract psw
00001A58	5020 8ED4		000010D4	1160+	ST	R2, CCPSW	to save CC
00001A5C	07FB			1161+	BR	R11	return
00001A60				1162+RE24	DC	0F	
00001A60				1163+	DROP	R5	
00001A60	F0F5F6F7 F8F9F0F1			1164	DC	XL16' F0F5F6F7F8F9F0F1F2F3F4F5F6F7F8F9'	V1 result
00001A68	F2F3F4F5 F6F7F8F9						
00001A70	56789012 34567890			1165	DC	XL16' 5678901234567890123456789012345D'	V2 source
00001A78	12345678 9012345D						
				1166			
				1167 * VUPKZH			m3= 4 (NSV=0, NV=1 , fake CS=0)
				1168	VRR_K	VUPKZH, 4, 0	
00001A80				1169+	DS	0FD	
00001A80		00001A80		1170+	USING	*, R5	base for test data and test routine
00001A80	00001A9C			1171+T25	DC	A(X25)	address of test routine
00001A84	0019			1172+	DC	H' 25'	test number
00001A86	00			1173+	DC	XL1' 00'	
00001A87	04			1174+	DC	HL1' 4'	&MB
00001A88	00			1175+	DC	HL1' 0'	cc
00001A89	07			1176+	DC	HL1' 7'	cc failed mask
00001A8A	E5E4D7D2 E9C84040			1177+	DC	CL8' VUPKZH'	instruction name
00001A94	00000010			1178+	DC	A(16)	result length
00001A98	00001AC0			1179+REA25	DC	A(RE25)	result address
				1180+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A9C				1181+X25	DS	0F	
00001A9C	E710 8F30 0006		00001130	1182+	VL	V1, V1FUDGE	pollute V1
00001AA2	E720 5050 0006		00001AD0	1183+	VL	V2, RE25+16	get V2 source
00001AA8	E612 0040 0054			1184+	VUPKZH	V1, V2, 4	test instruction
00001AAE	E710 8EF8 000E		000010F8	1185+	VST	V1, V10UTPUT	save
00001AB4	B98D 0020			1186+	EPSW	R2, R0	exptract psw
00001AB8	5020 8ED4		000010D4	1187+	ST	R2, CCPSW	to save CC
00001ABC	07FB			1188+	BR	R11	return
00001AC0				1189+RE25	DC	0F	
00001AC0				1190+	DROP	R5	
00001AC0	F0F1FFFF FFF5F6F7			1191	DC	XL16' F0F1FFFFFFFFF5F6F7F8F9F0F1F2F3F4F5'	V1 result
00001AC8	F8F9F0F1 F2F3F4F5						
00001AD0	1FFF5678 90123456			1192	DC	XL16' 1FFF567890123456789012345678901C'	V2 source
00001AD8	78901234 5678901C						
				1193			
				1194	VRR_K	VUPKZH, 4, 0	
00001AE0				1195+	DS	0FD	
00001AE0		00001AE0		1196+	USING	*, R5	base for test data and test routine
00001AE0	00001AFC			1197+T26	DC	A(X26)	address of test routine
00001AE4	001A			1198+	DC	H' 26'	test number
00001AE6	00			1199+	DC	XL1' 00'	
00001AE7	04			1200+	DC	HL1' 4'	&MB
00001AE8	00			1201+	DC	HL1' 0'	cc
00001AE9	07			1202+	DC	HL1' 7'	cc failed mask
00001AEA	E5E4D7D2 E9C84040			1203+	DC	CL8' VUPKZH'	instruction name
00001AF4	00000010			1204+	DC	A(16)	result length
00001AF8	00001B20			1205+REA26	DC	A(RE26)	result address
				1206+*			INSTRUCTION UNDER TEST ROUTINE
00001AFC				1207+X26	DS	0F	
00001AFC	E710 8F30 0006		00001130	1208+	VL	V1, V1FUDGE	pollute V1
00001B02	E720 5050 0006		00001B30	1209+	VL	V2, RE26+16	get V2 source
00001B08	E612 0040 0054			1210+	VUPKZH	V1, V2, 4	test instruction
00001B0E	E710 8EF8 000E		000010F8	1211+	VST	V1, V10UTPUT	save
00001B14	B98D 0020			1212+	EPSW	R2, R0	exptract psw
00001B18	5020 8ED4		000010D4	1213+	ST	R2, CCPSW	to save CC
00001B1C	07FB			1214+	BR	R11	return
00001B20				1215+RE26	DC	0F	
00001B20				1216+	DROP	R5	
00001B20	F0F5F6F7 F8F9F0F1			1217	DC	XL16' F0F5F6F7F8F9F0F1F2F3F4F5F6F7F8F9'	V1 result
00001B28	F2F3F4F5 F6F7F8F9						
00001B30	56789012 34567890			1218	DC	XL16' 56789012345678901234567890123459'	V2 source
00001B38	12345678 90123459						
				1219			
				1220 * VUPKZH			m3= 8 (NSV=1, NV=0 , fake CS=0)
				1221	VRR_K	VUPKZH, 8, 0	
00001B40				1222+	DS	0FD	
00001B40		00001B40		1223+	USING	*, R5	base for test data and test routine
00001B40	00001B5C			1224+T27	DC	A(X27)	address of test routine
00001B44	001B			1225+	DC	H' 27'	test number
00001B46	00			1226+	DC	XL1' 00'	
00001B47	08			1227+	DC	HL1' 8'	&MB
00001B48	00			1228+	DC	HL1' 0'	cc
00001B49	07			1229+	DC	HL1' 7'	cc failed mask
00001B4A	E5E4D7D2 E9C84040			1230+	DC	CL8' VUPKZH'	instruction name
00001B54	00000010			1231+	DC	A(16)	result length
00001B58	00001B80			1232+REA27	DC	A(RE27)	result address

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				1233+*		INSTRUCTION UNDER TEST ROUTINE	
00001B5C				1234+X27	DS	OF	
00001B5C	E710 8F30 0006		00001130	1235+	VL	V1, V1FUDGE	pollute V1
00001B62	E720 5050 0006		00001B90	1236+	VL	V2, RE27+16	get V2 source
00001B68	E612 0080 0054			1237+	VUPKZH	V1, V2, 8	test instruction
00001B6E	E710 8EF8 000E		000010F8	1238+	VST	V1, V10UTPUT	save
00001B74	B98D 0020			1239+	EPSW	R2, R0	exptract psw
00001B78	5020 8ED4		000010D4	1240+	ST	R2, CCPSW	to save CC
00001B7C	07FB			1241+	BR	R11	return
00001B80				1242+RE27	DC	OF	
00001B80				1243+	DROP	R5	
00001B80	F0F1F2F3 F4F5F6F7			1244	DC	XL16' F0F1F2F3F4F5F6F7F8F9F0F1F2F3F4F5'	V1 result
00001B88	F8F9F0F1 F2F3F4F5						
00001B90	12345678 90123456			1245	DC	XL16' 1234567890123456789012345678901C'	V2 source
00001B98	78901234 5678901C						
				1246			
				1247	VRR_K	VUPKZH, 8, 0	
00001BA0				1248+	DS	OFD	
00001BA0		00001BA0		1249+	USING	*, R5	base for test data and test routine
00001BA0	00001BBC			1250+T28	DC	A(X28)	address of test routine
00001BA4	001C			1251+	DC	H' 28'	test number
00001BA6	00			1252+	DC	XL1' 00'	
00001BA7	08			1253+	DC	HL1' 8'	&MB
00001BA8	00			1254+	DC	HL1' 0'	cc
00001BA9	07			1255+	DC	HL1' 7'	cc failed mask
00001BAA	E5E4D7D2 E9C84040			1256+	DC	CL8' VUPKZH'	instruction name
00001BB4	00000010			1257+	DC	A(16)	result length
00001BB8	00001BE0			1258+REA28	DC	A(RE28)	result address
				1259+*			INSTRUCTION UNDER TEST ROUTINE
00001BBC				1260+X28	DS	OF	
00001BBC	E710 8F30 0006		00001130	1261+	VL	V1, V1FUDGE	pollute V1
00001BC2	E720 5050 0006		00001BF0	1262+	VL	V2, RE28+16	get V2 source
00001BC8	E612 0080 0054			1263+	VUPKZH	V1, V2, 8	test instruction
00001BCE	E710 8EF8 000E		000010F8	1264+	VST	V1, V10UTPUT	save
00001BD4	B98D 0020			1265+	EPSW	R2, R0	exptract psw
00001BD8	5020 8ED4		000010D4	1266+	ST	R2, CCPSW	to save CC
00001BDC	07FB			1267+	BR	R11	return
00001BE0				1268+RE28	DC	OF	
00001BE0				1269+	DROP	R5	
00001BE0	F0F5F6F7 F8F9F0F1			1270	DC	XL16' F0F5F6F7F8F9F0F1F2F3F4F5F6F7F8F9'	V1 result
00001BE8	F2F3F4F5 F6F7F8F9						
00001BF0	56789012 34567890			1271	DC	XL16' 56789012345678901234567890123459'	V2 source
00001BF8	12345678 90123459						
				1272			
				1273 * VUPKZH			m3= 12 (NSV=1, NV=1 , fake CS=0)
				1274	VRR_K	VUPKZH, 12, 0	
00001C00				1275+	DS	OFD	
00001C00		00001C00		1276+	USING	*, R5	base for test data and test routine
00001C00	00001C1C			1277+T29	DC	A(X29)	address of test routine
00001C04	001D			1278+	DC	H' 29'	test number
00001C06	00			1279+	DC	XL1' 00'	
00001C07	0C			1280+	DC	HL1' 12'	&MB
00001C08	00			1281+	DC	HL1' 0'	cc
00001C09	07			1282+	DC	HL1' 7'	cc failed mask
00001C0A	E5E4D7D2 E9C84040			1283+	DC	CL8' VUPKZH'	instruction name
00001C14	00000010			1284+	DC	A(16)	result length

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C18	00001C40			1285+REA29	DC	A(RE29)	result address
				1286+*			INSTRUCTION UNDER TEST ROUTINE
00001C1C				1287+X29	DS	0F	
00001C1C	E710 8F30 0006		00001130	1288+	VL	V1, V1FUDGE	pollute V1
00001C22	E720 5050 0006		00001C50	1289+	VL	V2, RE29+16	get V2 source
00001C28	E612 00C0 0054			1290+	VUPKZH	V1, V2, 12	test instruction
00001C2E	E710 8EF8 000E		000010F8	1291+	VST	V1, V10UTPUT	save
00001C34	B98D 0020			1292+	EPSW	R2, R0	exptract psw
00001C38	5020 8ED4		000010D4	1293+	ST	R2, CCPSW	to save CC
00001C3C	07FB			1294+	BR	R11	return
00001C40				1295+RE29	DC	0F	
00001C40				1296+	DROP	R5	
00001C40	F0F1FFFF FFF5F6F7			1297	DC	XL16' F0F1FFFFFFFFF5F6F7F8F9F0F1F2F3F4F5'	V1 result
00001C48	F8F9F0F1 F2F3F4F5						
00001C50	1FFF5678 90123456			1298	DC	XL16' 1FFF567890123456789012345678901C'	V2 source
00001C58	78901234 5678901C						
				1299			
00001C60				1300	VRR_K	VUPKZH, 12, 0	
00001C60		00001C60		1301+	DS	0FD	
00001C60	00001C7C			1302+	USING	*, R5	base for test data and test routine
00001C64	001E			1303+T30	DC	A(X30)	address of test routine
00001C66	00			1304+	DC	H' 30'	test number
00001C66	00			1305+	DC	XL1' 00'	
00001C67	0C			1306+	DC	HL1' 12'	&MB
00001C68	00			1307+	DC	HL1' 0'	cc
00001C69	07			1308+	DC	HL1' 7'	cc failed mask
00001C6A	E5E4D7D2 E9C84040			1309+	DC	CL8' VUPKZH'	instruction name
00001C74	00000010			1310+	DC	A(16)	result length
00001C78	00001CA0			1311+REA30	DC	A(RE30)	result address
				1312+*			INSTRUCTION UNDER TEST ROUTINE
00001C7C				1313+X30	DS	0F	
00001C7C	E710 8F30 0006		00001130	1314+	VL	V1, V1FUDGE	pollute V1
00001C82	E720 5050 0006		00001CB0	1315+	VL	V2, RE30+16	get V2 source
00001C88	E612 00C0 0054			1316+	VUPKZH	V1, V2, 12	test instruction
00001C8E	E710 8EF8 000E		000010F8	1317+	VST	V1, V10UTPUT	save
00001C94	B98D 0020			1318+	EPSW	R2, R0	exptract psw
00001C98	5020 8ED4		000010D4	1319+	ST	R2, CCPSW	to save CC
00001C9C	07FB			1320+	BR	R11	return
00001CA0				1321+RE30	DC	0F	
00001CA0				1322+	DROP	R5	
00001CA0	F0F5F6F7 F8F9F0F1			1323	DC	XL16' F0F5F6F7F8F9F0F1F2F3F4F5F6F7F8F9'	V1 result
00001CA8	F2F3F4F5 F6F7F8F9						
00001CB0	56789012 34567890			1324	DC	XL16' 56789012345678901234567890123459'	V2 source
00001CB8	12345678 90123459						
				1325			
				1326 *			
				1327 *	VUPKZL	- VECTOR UNPACK ZONED LOW	
				1328 *			
				1329 *	NOTE NOTE: VUPKZL does NOT set the condition code!		
				1330 *	m3 bit 3 should be ZERO (which matches the CS bit of VCLZDP		
				1331 *	so CC checking should be skipped!!)		
				1332 *			
				1333 *	VUPKZL simple	m3= 0 (NSV=0, NV=0 , P1=0, fake CS=0)	
				1334 *		m3= 2 (NSV=0, NV=1 , P1=1, fake CS=0)	
				1335 *		m3= 4 (NSV=0, NV=1 , P1=0, fake CS=0)	
				1336 *		m3= 6 (NSV=0, NV=1 , P1=1, fake CS=0)	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1337 *	m3= 8 (NSV=1, NV=0 , P1=0, fake CS=0)
				1338 *	m3= 10 (NSV=1, NV=0 , P1=1, fake CS=0)
				1339 *	m3= 12 (NSV=1, NV=1 , P1=0, fake CS=0)
				1340 *	m3= 14 (NSV=1, NV=1 , P1=1, fake CS=0)
				1341	VRR_K VUPKZL, 0, 0
00001CC0				1342+	DS OFD
00001CC0		00001CC0		1343+	USING *, R5
00001CC0	00001CDC			1344+T31	DC A(X31)
00001CC4	001F			1345+	DC H' 31'
00001CC6	00			1346+	DC XL1' 00'
00001CC7	00			1347+	DC HL1' 0'
00001CC8	00			1348+	DC HL1' 0'
00001CC9	07			1349+	DC HL1' 7'
00001CCA	E5E4D7D2 E9D34040			1350+	DC CL8' VUPKZL'
00001CD4	00000010			1351+	DC A(16)
00001CD8	00001D00			1352+REA31	DC A(RE31)
				1353+*	INSTRUCTION UNDER TEST ROUTINE
00001CDC				1354+X31	DS OF
00001CDC	E710 8F30 0006		00001130	1355+	VL V1, V1FUDGE
00001CE2	E720 5050 0006		00001D10	1356+	VL V2, RE31+16
00001CE8	E612 0000 005C			1357+	VUPKZL V1, V2, 0
00001CEE	E710 8EF8 000E		000010F8	1358+	VST V1, V10UTPUT
00001CF4	B98D 0020			1359+	EPSW R2, R0
00001CF8	5020 8ED4		000010D4	1360+	ST R2, CCPSW
00001CFC	07FB			1361+	BR R11
00001D00				1362+RE31	DC OF
00001D00				1363+	DROP R5
00001D00	F6F7F8F9 F0F1F2F3			1364	DC XL16' F6F7F8F9F0F1F2F3F4F5F6F7F8F9F0C1'
00001D08	F4F5F6F7 F8F9F0C1				V1 result
00001D10	12345678 90123456			1365	DC XL16' 1234567890123456789012345678901C'
00001D18	78901234 5678901C				V2 source
				1366	
				1367	VRR_K VUPKZL, 0, 0
00001D20				1368+	DS OFD
00001D20		00001D20		1369+	USING *, R5
00001D20	00001D3C			1370+T32	DC A(X32)
00001D24	0020			1371+	DC H' 32'
00001D26	00			1372+	DC XL1' 00'
00001D27	00			1373+	DC HL1' 0'
00001D28	00			1374+	DC HL1' 0'
00001D29	07			1375+	DC HL1' 7'
00001D2A	E5E4D7D2 E9D34040			1376+	DC CL8' VUPKZL'
00001D34	00000010			1377+	DC A(16)
00001D38	00001D60			1378+REA32	DC A(RE32)
				1379+*	INSTRUCTION UNDER TEST ROUTINE
00001D3C				1380+X32	DS OF
00001D3C	E710 8F30 0006		00001130	1381+	VL V1, V1FUDGE
00001D42	E720 5050 0006		00001D70	1382+	VL V2, RE32+16
00001D48	E612 0000 005C			1383+	VUPKZL V1, V2, 0
00001D4E	E710 8EF8 000E		000010F8	1384+	VST V1, V10UTPUT
00001D54	B98D 0020			1385+	EPSW R2, R0
00001D58	5020 8ED4		000010D4	1386+	ST R2, CCPSW
00001D5C	07FB			1387+	BR R11
00001D60				1388+RE32	DC OF
00001D60				1389+	DROP R5
00001D60	F0F1F2F3 F4F5F6F7			1390	DC XL16' F0F1F2F3F4F5F6F7F8F9F0F1F2F3F4D5'
					V1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D68	F8F9F0F1 F2F3F4D5						
00001D70	56789012 34567890			1391	DC	XL16' 5678901234567890123456789012345D'	V2 source
00001D78	12345678 9012345D						
				1392			
				1393	* VUPKZL	m3= 2 (NSV=0, NV=1 , P1=1, fake CS=0)	
				1394	VRR_K VUPKZL, 2, 0		
00001D80				1395+	DS	OFD	
00001D80		00001D80		1396+	USING	*, R5	base for test data and test routine
00001D80	00001D9C			1397+T33	DC	A(X33)	address of test routine
00001D84	0021			1398+	DC	H' 33'	test number
00001D86	00			1399+	DC	XL1' 00'	
00001D87	02			1400+	DC	HL1' 2'	&MB
00001D88	00			1401+	DC	HL1' 0'	cc
00001D89	07			1402+	DC	HL1' 7'	cc failed mask
00001D8A	E5E4D7D2 E9D34040			1403+	DC	CL8' VUPKZL'	instruction name
00001D94	00000010			1404+	DC	A(16)	result length
00001D98	00001DC0			1405+REA33	DC	A(RE33)	result address
				1406+*			INSTRUCTION UNDER TEST ROUTINE
00001D9C				1407+X33	DS	OF	
00001D9C	E710 8F30 0006		00001130	1408+	VL	V1, V1FUDGE	pollute V1
00001DA2	E720 5050 0006		00001DD0	1409+	VL	V2, RE33+16	get V2 source
00001DA8	E612 0020 005C			1410+	VUPKZL	V1, V2, 2	test instruction
00001DAE	E710 8EF8 000E		000010F8	1411+	VST	V1, V10UTPUT	save
00001DB4	B98D 0020			1412+	EPSW	R2, R0	exptract psw
00001DB8	5020 8ED4		000010D4	1413+	ST	R2, CCPSW	to save CC
00001DBC	07FB			1414+	BR	R11	return
00001DC0				1415+RE33	DC	OF	
00001DC0				1416+	DROP	R5	
00001DC0	F6F7F8F9 F0F1F2F3			1417	DC	XL16' F6F7F8F9F0F1F2F3F4F5F6F7F8F9F0F1'	V1 result
00001DC8	F4F5F6F7 F8F9F0F1						
00001DD0	12345678 90123456			1418	DC	XL16' 1234567890123456789012345678901C'	V2 source
00001DD8	78901234 5678901C						
				1419			
				1420	VRR_K VUPKZL, 2, 0		
00001DE0				1421+	DS	OFD	
00001DE0		00001DE0		1422+	USING	*, R5	base for test data and test routine
00001DE0	00001DFC			1423+T34	DC	A(X34)	address of test routine
00001DE4	0022			1424+	DC	H' 34'	test number
00001DE6	00			1425+	DC	XL1' 00'	
00001DE7	02			1426+	DC	HL1' 2'	&MB
00001DE8	00			1427+	DC	HL1' 0'	cc
00001DE9	07			1428+	DC	HL1' 7'	cc failed mask
00001DEA	E5E4D7D2 E9D34040			1429+	DC	CL8' VUPKZL'	instruction name
00001DF4	00000010			1430+	DC	A(16)	result length
00001DF8	00001E20			1431+REA34	DC	A(RE34)	result address
				1432+*			INSTRUCTION UNDER TEST ROUTINE
00001DFC				1433+X34	DS	OF	
00001DFC	E710 8F30 0006		00001130	1434+	VL	V1, V1FUDGE	pollute V1
00001E02	E720 5050 0006		00001E30	1435+	VL	V2, RE34+16	get V2 source
00001E08	E612 0020 005C			1436+	VUPKZL	V1, V2, 2	test instruction
00001E0E	E710 8EF8 000E		000010F8	1437+	VST	V1, V10UTPUT	save
00001E14	B98D 0020			1438+	EPSW	R2, R0	exptract psw
00001E18	5020 8ED4		000010D4	1439+	ST	R2, CCPSW	to save CC
00001E1C	07FB			1440+	BR	R11	return
00001E20				1441+RE34	DC	OF	
00001E20				1442+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001E20	F0F1F2F3 F4F5F6F7			1443	DC	XL16' F0F1F2F3F4F5F6F7F8F9F0F1F2F3F4F5'	V1 result
00001E28	F8F9F0F1 F2F3F4F5						
00001E30	56789012 34567890			1444	DC	XL16' 5678901234567890123456789012345D'	V2 source
00001E38	12345678 9012345D						
				1445			
				1446	* VUPKZL	m3= 4 (NSV=0, NV=1 , P1=0, fake CS=0)	
				1447	VRR_K	VUPKZL, 4, 0	
00001E40				1448+	DS	OFD	
00001E40		00001E40		1449+	USING	*, R5	base for test data and test routine
00001E40	00001E5C			1450+T35	DC	A(X35)	address of test routine
00001E44	0023			1451+	DC	H' 35'	test number
00001E46	00			1452+	DC	XL1' 00'	
00001E47	04			1453+	DC	HL1' 4'	&MB
00001E48	00			1454+	DC	HL1' 0'	cc
00001E49	07			1455+	DC	HL1' 7'	cc failed mask
00001E4A	E5E4D7D2 E9D34040			1456+	DC	CL8' VUPKZL'	instruction name
00001E54	00000010			1457+	DC	A(16)	result length
00001E58	00001E80			1458+REA35	DC	A(RE35)	result address
				1459+*			INSTRUCTION UNDER TEST ROUTINE
00001E5C				1460+X35	DS	OF	
00001E5C	E710 8F30 0006		00001130	1461+	VL	V1, V1FUDGE	pollute V1
00001E62	E720 5050 0006		00001E90	1462+	VL	V2, RE35+16	get V2 source
00001E68	E612 0040 005C			1463+	VUPKZL	V1, V2, 4	test instruction
00001E6E	E710 8EF8 000E		000010F8	1464+	VST	V1, V10UTPUT	save
00001E74	B98D 0020			1465+	EPSW	R2, R0	exptract psw
00001E78	5020 8ED4		000010D4	1466+	ST	R2, CCPSW	to save CC
00001E7C	07FB			1467+	BR	R11	return
00001E80				1468+RE35	DC	OF	
00001E80				1469+	DROP	R5	
00001E80	F6F7F8F9 F0F1F2F3			1470	DC	XL16' F6F7F8F9F0F1F2F3F4F5F6F7F8F9F091'	V1 result
00001E88	F4F5F6F7 F8F9F091						
00001E90	12345678 90123456			1471	DC	XL16' 12345678901234567890123456789019'	V2 source
00001E98	78901234 56789019						
				1472			
				1473	VRR_K	VUPKZL, 4, 0	
00001EA0				1474+	DS	OFD	
00001EA0		00001EA0		1475+	USING	*, R5	base for test data and test routine
00001EA0	00001EBC			1476+T36	DC	A(X36)	address of test routine
00001EA4	0024			1477+	DC	H' 36'	test number
00001EA6	00			1478+	DC	XL1' 00'	
00001EA7	04			1479+	DC	HL1' 4'	&MB
00001EA8	00			1480+	DC	HL1' 0'	cc
00001EA9	07			1481+	DC	HL1' 7'	cc failed mask
00001EAA	E5E4D7D2 E9D34040			1482+	DC	CL8' VUPKZL'	instruction name
00001EB4	00000010			1483+	DC	A(16)	result length
00001EB8	00001EE0			1484+REA36	DC	A(RE36)	result address
				1485+*			INSTRUCTION UNDER TEST ROUTINE
00001EBC				1486+X36	DS	OF	
00001EBC	E710 8F30 0006		00001130	1487+	VL	V1, V1FUDGE	pollute V1
00001EC2	E720 5050 0006		00001EF0	1488+	VL	V2, RE36+16	get V2 source
00001EC8	E612 0040 005C			1489+	VUPKZL	V1, V2, 4	test instruction
00001ECE	E710 8EF8 000E		000010F8	1490+	VST	V1, V10UTPUT	save
00001ED4	B98D 0020			1491+	EPSW	R2, R0	exptract psw
00001ED8	5020 8ED4		000010D4	1492+	ST	R2, CCPSW	to save CC
00001EDC	07FB			1493+	BR	R11	return
00001EE0				1494+RE36	DC	OF	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001EE0				1495+	DROP R5	
00001EE0	F0F1F2F3 F4F5F6F7			1496	DC	XL16' F0F1F2F3F4F5F6F7F8F9FFF1F2F3F4D5' V1 result
00001EE8	F8F9FFF1 F2F3F4D5					
00001EF0	56789012 34567890			1497	DC	XL16' 5678901234567890123456789F12345D' V2 source
00001EF8	12345678 9F12345D					
				1498		
				1499 * VUPKZL		m3= 6 (NSV=0, NV=1 , P1=1, fake CS=0
				1500	VRR_K VUPKZL, 6, 0	
00001F00				1501+	DS	OFD
00001F00		00001F00		1502+	USING *, R5	base for test data and test routine
00001F00	00001F1C			1503+T37	DC	A(X37) address of test routine
00001F04	0025			1504+	DC	H' 37' test number
00001F06	00			1505+	DC	XL1' 00'
00001F07	06			1506+	DC	HL1' 6' &MB
00001F08	00			1507+	DC	HL1' 0' cc
00001F09	07			1508+	DC	HL1' 7' cc failed mask
00001F0A	E5E4D7D2 E9D34040			1509+	DC	CL8' VUPKZL' instruction name
00001F14	00000010			1510+	DC	A(16) result length
00001F18	00001F40			1511+REA37	DC	A(RE37) result address
				1512+*		INSTRUCTION UNDER TEST ROUTINE
00001F1C				1513+X37	DS	OF
00001F1C	E710 8F30 0006		00001130	1514+	VL	V1, V1FUDGE pollute V1
00001F22	E720 5050 0006		00001F50	1515+	VL	V2, RE37+16 get V2 source
00001F28	E612 0060 005C			1516+	VUPKZL V1, V2, 6	test instruction
00001F2E	E710 8EF8 000E		000010F8	1517+	VST	V1, V10UTPUT save
00001F34	B98D 0020			1518+	EPSW R2, R0	exptract psw
00001F38	5020 8ED4		000010D4	1519+	ST	R2, CCPSW to save CC
00001F3C	07FB			1520+	BR	R11 return
00001F40				1521+RE37	DC	OF
00001F40				1522+	DROP R5	
00001F40	F6F7F8F9 F0F1F2F3			1523	DC	XL16' F6F7F8F9F0F1F2F3F4F5F6F7F8F9F0F1' V1 result
00001F48	F4F5F6F7 F8F9F0F1					
00001F50	12345678 90123456			1524	DC	XL16' 12345678901234567890123456789019' V2 source
00001F58	78901234 56789019					
				1525		
				1526	VRR_K VUPKZL, 6, 0	
00001F60				1527+	DS	OFD
00001F60		00001F60		1528+	USING *, R5	base for test data and test routine
00001F60	00001F7C			1529+T38	DC	A(X38) address of test routine
00001F64	0026			1530+	DC	H' 38' test number
00001F66	00			1531+	DC	XL1' 00'
00001F67	06			1532+	DC	HL1' 6' &MB
00001F68	00			1533+	DC	HL1' 0' cc
00001F69	07			1534+	DC	HL1' 7' cc failed mask
00001F6A	E5E4D7D2 E9D34040			1535+	DC	CL8' VUPKZL' instruction name
00001F74	00000010			1536+	DC	A(16) result length
00001F78	00001FA0			1537+REA38	DC	A(RE38) result address
				1538+*		INSTRUCTION UNDER TEST ROUTINE
00001F7C				1539+X38	DS	OF
00001F7C	E710 8F30 0006		00001130	1540+	VL	V1, V1FUDGE pollute V1
00001F82	E720 5050 0006		00001FB0	1541+	VL	V2, RE38+16 get V2 source
00001F88	E612 0060 005C			1542+	VUPKZL V1, V2, 6	test instruction
00001F8E	E710 8EF8 000E		000010F8	1543+	VST	V1, V10UTPUT save
00001F94	B98D 0020			1544+	EPSW R2, R0	exptract psw
00001F98	5020 8ED4		000010D4	1545+	ST	R2, CCPSW to save CC
00001F9C	07FB			1546+	BR	R11 return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001FA0				1547+RE38	DC	0F	
00001FA0				1548+	DROP	R5	
00001FA0	F0F1F2F3 F4F5F6F7			1549	DC	XL16' F0F1F2F3F4F5F6F7F8F9FFF1F2F3F4F5'	V1 result
00001FA8	F8F9FFF1 F2F3F4F5						
00001FB0	56789012 34567890			1550	DC	XL16' 5678901234567890123456789F12345D'	V2 source
00001FB8	12345678 9F12345D						
				1551			
				1552 * VUPKZL		m3= 8 (NSV=1, NV=0 , P1=0, fake CS=0)	
				1553	VRR_K	VUPKZL, 8, 0	
00001FC0				1554+	DS	0FD	
00001FC0		00001FC0		1555+	USING	*, R5	base for test data and test routine
00001FC0	00001FDC			1556+T39	DC	A(X39)	address of test routine
00001FC4	0027			1557+	DC	H' 39'	test number
00001FC6	00			1558+	DC	XL1' 00'	
00001FC7	08			1559+	DC	HL1' 8'	&MB
00001FC8	00			1560+	DC	HL1' 0'	cc
00001FC9	07			1561+	DC	HL1' 7'	cc failed mask
00001FCA	E5E4D7D2 E9D34040			1562+	DC	CL8' VUPKZL'	instruction name
00001FD4	00000010			1563+	DC	A(16)	result length
00001FD8	00002000			1564+REA39	DC	A(RE39)	result address
				1565+*			INSTRUCTION UNDER TEST ROUTINE
00001FDC				1566+X39	DS	0F	
00001FDC	E710 8F30 0006		00001130	1567+	VL	V1, V1FUDGE	pollute V1
00001FE2	E720 5050 0006		00002010	1568+	VL	V2, RE39+16	get V2 source
00001FE8	E612 0080 005C			1569+	VUPKZL	V1, V2, 8	test instruction
00001FEE	E710 8EF8 000E		000010F8	1570+	VST	V1, V10UTPUT	save
00001FF4	B98D 0020			1571+	EPSW	R2, R0	exptract psw
00001FF8	5020 8ED4		000010D4	1572+	ST	R2, CCPSW	to save CC
00001FFC	07FB			1573+	BR	R11	return
00002000				1574+RE39	DC	0F	
00002000				1575+	DROP	R5	
00002000	F6F7F8F9 F0F1F2F3			1576	DC	XL16' F6F7F8F9F0F1F2F3F4F5F6F7F8F9F091'	V1 result
00002008	F4F5F6F7 F8F9F091						
00002010	12345678 90123456			1577	DC	XL16' 12345678901234567890123456789019'	V2 source
00002018	78901234 56789019						
				1578			
				1579	VRR_K	VUPKZL, 8, 0	
00002020				1580+	DS	0FD	
00002020		00002020		1581+	USING	*, R5	base for test data and test routine
00002020	0000203C			1582+T40	DC	A(X40)	address of test routine
00002024	0028			1583+	DC	H' 40'	test number
00002026	00			1584+	DC	XL1' 00'	
00002027	08			1585+	DC	HL1' 8'	&MB
00002028	00			1586+	DC	HL1' 0'	cc
00002029	07			1587+	DC	HL1' 7'	cc failed mask
0000202A	E5E4D7D2 E9D34040			1588+	DC	CL8' VUPKZL'	instruction name
00002034	00000010			1589+	DC	A(16)	result length
00002038	00002060			1590+REA40	DC	A(RE40)	result address
				1591+*			INSTRUCTION UNDER TEST ROUTINE
0000203C				1592+X40	DS	0F	
0000203C	E710 8F30 0006		00001130	1593+	VL	V1, V1FUDGE	pollute V1
00002042	E720 5050 0006		00002070	1594+	VL	V2, RE40+16	get V2 source
00002048	E612 0080 005C			1595+	VUPKZL	V1, V2, 8	test instruction
0000204E	E710 8EF8 000E		000010F8	1596+	VST	V1, V10UTPUT	save
00002054	B98D 0020			1597+	EPSW	R2, R0	exptract psw
00002058	5020 8ED4		000010D4	1598+	ST	R2, CCPSW	to save CC

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000205C	07FB			1599+	BR	R11	return
00002060				1600+RE40	DC	0F	
00002060				1601+	DROP	R5	
00002060	F0F1F2F3 F4F5F6F7			1602	DC	XL16' F0F1F2F3F4F5F6F7F8F9F0F1F2F3F4A5'	V1 result
00002068	F8F9F0F1 F2F3F4A5						
00002070	56789012 34567890			1603	DC	XL16' 5678901234567890123456789012345A'	V2 source
00002078	12345678 9012345A						
				1604			
				1605 * VUPKZL			m3= 10 (NSV=1, NV=0 , P1=1, fake CS=0)
				1606	VRR_K	VUPKZL, 10, 0	
00002080				1607+	DS	0FD	
00002080		00002080		1608+	USING	*, R5	base for test data and test routine
00002080	0000209C			1609+T41	DC	A(X41)	address of test routine
00002084	0029			1610+	DC	H' 41'	test number
00002086	00			1611+	DC	XL1' 00'	
00002087	0A			1612+	DC	HL1' 10'	&MB
00002088	00			1613+	DC	HL1' 0'	cc
00002089	07			1614+	DC	HL1' 7'	cc failed mask
0000208A	E5E4D7D2 E9D34040			1615+	DC	CL8' VUPKZL'	instruction name
00002094	00000010			1616+	DC	A(16)	result length
00002098	000020C0			1617+REA41	DC	A(RE41)	result address
				1618+*			INSTRUCTION UNDER TEST ROUTINE
0000209C				1619+X41	DS	0F	
0000209C	E710 8F30 0006		00001130	1620+	VL	V1, V1FUDGE	pollute V1
000020A2	E720 5050 0006		000020D0	1621+	VL	V2, RE41+16	get V2 source
000020A8	E612 00A0 005C			1622+	VUPKZL	V1, V2, 10	test instruction
000020AE	E710 8EF8 000E		000010F8	1623+	VST	V1, V10UTPUT	save
000020B4	B98D 0020			1624+	EPSW	R2, R0	exptract psw
000020B8	5020 8ED4		000010D4	1625+	ST	R2, CCPSW	to save CC
000020BC	07FB			1626+	BR	R11	return
000020C0				1627+RE41	DC	0F	
000020C0				1628+	DROP	R5	
000020C0	F6F7F8F9 F0F1F2F3			1629	DC	XL16' F6F7F8F9F0F1F2F3F4F5F6F7F8F9F0F1'	V1 result
000020C8	F4F5F6F7 F8F9F0F1						
000020D0	12345678 90123456			1630	DC	XL16' 12345678901234567890123456789019'	V2 source
000020D8	78901234 56789019						
				1631			
				1632	VRR_K	VUPKZL, 10, 0	
000020E0				1633+	DS	0FD	
000020E0		000020E0		1634+	USING	*, R5	base for test data and test routine
000020E0	000020FC			1635+T42	DC	A(X42)	address of test routine
000020E4	002A			1636+	DC	H' 42'	test number
000020E6	00			1637+	DC	XL1' 00'	
000020E7	0A			1638+	DC	HL1' 10'	&MB
000020E8	00			1639+	DC	HL1' 0'	cc
000020E9	07			1640+	DC	HL1' 7'	cc failed mask
000020EA	E5E4D7D2 E9D34040			1641+	DC	CL8' VUPKZL'	instruction name
000020F4	00000010			1642+	DC	A(16)	result length
000020F8	00002120			1643+REA42	DC	A(RE42)	result address
				1644+*			INSTRUCTION UNDER TEST ROUTINE
000020FC				1645+X42	DS	0F	
000020FC	E710 8F30 0006		00001130	1646+	VL	V1, V1FUDGE	pollute V1
00002102	E720 5050 0006		00002130	1647+	VL	V2, RE42+16	get V2 source
00002108	E612 00A0 005C			1648+	VUPKZL	V1, V2, 10	test instruction
0000210E	E710 8EF8 000E		000010F8	1649+	VST	V1, V10UTPUT	save
00002114	B98D 0020			1650+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002118	5020 8ED4		000010D4	1651+	ST	R2, CCPSW	to save CC
0000211C	07FB			1652+	BR	R11	return
00002120				1653+RE42	DC	0F	
00002120				1654+	DROP	R5	
00002120	F0F1F2F3 F4F5F6F7			1655	DC	XL16' F0F1F2F3F4F5F6F7F8F9F0F1F2F3F4F5'	V1 result
00002128	F8F9F0F1 F2F3F4F5						
00002130	56789012 34567890			1656	DC	XL16' 5678901234567890123456789012345A'	V2 source
00002138	12345678 9012345A						
				1657			
				1658 * VUPKZL			m3= 12 (NSV=1, NV=1 , P1=0, fake CS=0)
				1659	VRR_K	VUPKZL, 12, 0	
00002140				1660+	DS	0FD	
00002140		00002140		1661+	USING	*, R5	base for test data and test routine
00002140	0000215C			1662+T43	DC	A(X43)	address of test routine
00002144	002B			1663+	DC	H' 43'	test number
00002146	00			1664+	DC	XL1' 00'	
00002147	0C			1665+	DC	HL1' 12'	&MB
00002148	00			1666+	DC	HL1' 0'	cc
00002149	07			1667+	DC	HL1' 7'	cc failed mask
0000214A	E5E4D7D2 E9D34040			1668+	DC	CL8' VUPKZL'	instruction name
00002154	00000010			1669+	DC	A(16)	result length
00002158	00002180			1670+REA43	DC	A(RE43)	result address
				1671+*			INSTRUCTION UNDER TEST ROUTINE
0000215C				1672+X43	DS	0F	
0000215C	E710 8F30 0006		00001130	1673+	VL	V1, V1FUDGE	pollute V1
00002162	E720 5050 0006		00002190	1674+	VL	V2, RE43+16	get V2 source
00002168	E612 00C0 005C			1675+	VUPKZL	V1, V2, 12	test instruction
0000216E	E710 8EF8 000E		000010F8	1676+	VST	V1, V10UTPUT	save
00002174	B98D 0020			1677+	EPSW	R2, R0	exptract psw
00002178	5020 8ED4		000010D4	1678+	ST	R2, CCPSW	to save CC
0000217C	07FB			1679+	BR	R11	return
00002180				1680+RE43	DC	0F	
00002180				1681+	DROP	R5	
00002180	F6F7F8F9 FDF1F2F3			1682	DC	XL16' F6F7F8F9FDF1F2F3F4F5F6F7F8F9F091'	V1 result
00002188	F4F5F6F7 F8F9F091						
00002190	12345678 90123456			1683	DC	XL16' 1234567890123456789D123456789019'	V2 source
00002198	789D1234 56789019						
				1684			
				1685	VRR_K	VUPKZL, 12, 0	
000021A0				1686+	DS	0FD	
000021A0		000021A0		1687+	USING	*, R5	base for test data and test routine
000021A0	000021BC			1688+T44	DC	A(X44)	address of test routine
000021A4	002C			1689+	DC	H' 44'	test number
000021A6	00			1690+	DC	XL1' 00'	
000021A7	0C			1691+	DC	HL1' 12'	&MB
000021A8	00			1692+	DC	HL1' 0'	cc
000021A9	07			1693+	DC	HL1' 7'	cc failed mask
000021AA	E5E4D7D2 E9D34040			1694+	DC	CL8' VUPKZL'	instruction name
000021B4	00000010			1695+	DC	A(16)	result length
000021B8	000021E0			1696+REA44	DC	A(RE44)	result address
				1697+*			INSTRUCTION UNDER TEST ROUTINE
000021BC				1698+X44	DS	0F	
000021BC	E710 8F30 0006		00001130	1699+	VL	V1, V1FUDGE	pollute V1
000021C2	E720 5050 0006		000021F0	1700+	VL	V2, RE44+16	get V2 source
000021C8	E612 00C0 005C			1701+	VUPKZL	V1, V2, 12	test instruction
000021CE	E710 8EF8 000E		000010F8	1702+	VST	V1, V10UTPUT	save

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000021D4	B98D 0020			1703+	EPSW	R2, R0	exptract psw
000021D8	5020 8ED4		000010D4	1704+	ST	R2, CCPSW	to save CC
000021DC	07FB			1705+	BR	R11	return
000021E0				1706+RE44	DC	0F	
000021E0				1707+	DROP	R5	
000021E0	F0F1F2F3 F4F5F6F7			1708	DC	XL16' F0F1F2F3F4F5F6F7F8F9FBF1F2F3F415'	V1 result
000021E8	F8F9FBF1 F2F3F415						
000021F0	56789012 34567890			1709	DC	XL16' 5678901234567890123456789B123451'	V2 source
000021F8	12345678 9B123451						
				1710			
				1711 * VUPKZL			m3= 14 (NSV=1, NV=1 , P1=1, fake CS=0)
				1712	VRR_K	VUPKZL, 14, 0	
00002200				1713+	DS	0FD	
00002200		00002200		1714+	USING	*, R5	base for test data and test routine
00002200	0000221C			1715+T45	DC	A(X45)	address of test routine
00002204	002D			1716+	DC	H' 45'	test number
00002206	00			1717+	DC	XL1' 00'	
00002207	0E			1718+	DC	HL1' 14'	&MB
00002208	00			1719+	DC	HL1' 0'	cc
00002209	07			1720+	DC	HL1' 7'	cc failed mask
0000220A	E5E4D7D2 E9D34040			1721+	DC	CL8' VUPKZL'	instruction name
00002214	00000010			1722+	DC	A(16)	result length
00002218	00002240			1723+REA45	DC	A(RE45)	result address
				1724+*			INSTRUCTION UNDER TEST ROUTINE
0000221C				1725+X45	DS	0F	
0000221C	E710 8F30 0006		00001130	1726+	VL	V1, V1FUDGE	pollute V1
00002222	E720 5050 0006		00002250	1727+	VL	V2, RE45+16	get V2 source
00002228	E612 00E0 005C			1728+	VUPKZL	V1, V2, 14	test instruction
0000222E	E710 8EF8 000E		000010F8	1729+	VST	V1, V10UTPUT	save
00002234	B98D 0020			1730+	EPSW	R2, R0	exptract psw
00002238	5020 8ED4		000010D4	1731+	ST	R2, CCPSW	to save CC
0000223C	07FB			1732+	BR	R11	return
00002240				1733+RE45	DC	0F	
00002240				1734+	DROP	R5	
00002240	F6F7F8F9 FDF1F2F3			1735	DC	XL16' F6F7F8F9FDF1F2F3F4F5F6F7F8F9F0F1'	V1 result
00002248	F4F5F6F7 F8F9F0F1						
00002250	12345678 90123456			1736	DC	XL16' 1234567890123456789D123456789019'	V2 source
00002258	789D1234 56789019						
				1737			
				1738	VRR_K	VUPKZL, 14, 0	
00002260				1739+	DS	0FD	
00002260		00002260		1740+	USING	*, R5	base for test data and test routine
00002260	0000227C			1741+T46	DC	A(X46)	address of test routine
00002264	002E			1742+	DC	H' 46'	test number
00002266	00			1743+	DC	XL1' 00'	
00002267	0E			1744+	DC	HL1' 14'	&MB
00002268	00			1745+	DC	HL1' 0'	cc
00002269	07			1746+	DC	HL1' 7'	cc failed mask
0000226A	E5E4D7D2 E9D34040			1747+	DC	CL8' VUPKZL'	instruction name
00002274	00000010			1748+	DC	A(16)	result length
00002278	000022A0			1749+REA46	DC	A(RE46)	result address
				1750+*			INSTRUCTION UNDER TEST ROUTINE
0000227C				1751+X46	DS	0F	
0000227C	E710 8F30 0006		00001130	1752+	VL	V1, V1FUDGE	pollute V1
00002282	E720 5050 0006		000022B0	1753+	VL	V2, RE46+16	get V2 source
00002288	E612 00E0 005C			1754+	VUPKZL	V1, V2, 14	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000228E	E710 8EF8 000E		000010F8	1755+	VST	V1, V10	OUTPUT	save
00002294	B98D 0020			1756+	EPSW	R2, R0		extract psw
00002298	5020 8ED4		000010D4	1757+	ST	R2, CCPSW		to save CC
0000229C	07FB			1758+	BR	R11		return
000022A0				1759+RE46	DC	0F		
000022A0				1760+	DROP	R5		
000022A0	F0F1F2F3 F4F5F6F7			1761	DC	XL16' F0F1F2F3F4F5F6F7F8F9F9FBF1F2F3F4F5'		V1 result
000022A8	F8F9FBF1 F2F3F4F5							
000022B0	56789012 34567890			1762	DC	XL16' 5678901234567890123456789B123451'		V2 source
000022B8	12345678 9B123451							
				1763				
000022C0	00000000			1764	DC	F' 0'	END OF TABLE	
000022C4	00000000			1765	DC	F' 0'		
				1766 *				
				1767 *		table of pointers to individual load test		
				1768 *				
000022C8				1769 E6TESTS	DS	0F		
				1770	PTTABLE			
000022C8				1771+TTABLE	DS	0F		
000022C8	00001180			1772+	DC	A(T1)	address of test	
000022CC	000011E0			1773+	DC	A(T2)	address of test	
000022D0	00001240			1774+	DC	A(T3)	address of test	
000022D4	000012A0			1775+	DC	A(T4)	address of test	
000022D8	00001300			1776+	DC	A(T5)	address of test	
000022DC	00001360			1777+	DC	A(T6)	address of test	
000022E0	000013C0			1778+	DC	A(T7)	address of test	
000022E4	00001420			1779+	DC	A(T8)	address of test	
000022E8	00001480			1780+	DC	A(T9)	address of test	
000022EC	000014E0			1781+	DC	A(T10)	address of test	
000022F0	00001540			1782+	DC	A(T11)	address of test	
000022F4	000015A0			1783+	DC	A(T12)	address of test	
000022F8	00001600			1784+	DC	A(T13)	address of test	
000022FC	00001660			1785+	DC	A(T14)	address of test	
00002300	000016C0			1786+	DC	A(T15)	address of test	
00002304	00001720			1787+	DC	A(T16)	address of test	
00002308	00001780			1788+	DC	A(T17)	address of test	
0000230C	000017E0			1789+	DC	A(T18)	address of test	
00002310	00001840			1790+	DC	A(T19)	address of test	
00002314	000018A0			1791+	DC	A(T20)	address of test	
00002318	00001900			1792+	DC	A(T21)	address of test	
0000231C	00001960			1793+	DC	A(T22)	address of test	
00002320	000019C0			1794+	DC	A(T23)	address of test	
00002324	00001A20			1795+	DC	A(T24)	address of test	
00002328	00001A80			1796+	DC	A(T25)	address of test	
0000232C	00001AE0			1797+	DC	A(T26)	address of test	
00002330	00001B40			1798+	DC	A(T27)	address of test	
00002334	00001BA0			1799+	DC	A(T28)	address of test	
00002338	00001C00			1800+	DC	A(T29)	address of test	
0000233C	00001C60			1801+	DC	A(T30)	address of test	
00002340	00001CC0			1802+	DC	A(T31)	address of test	
00002344	00001D20			1803+	DC	A(T32)	address of test	
00002348	00001D80			1804+	DC	A(T33)	address of test	
0000234C	00001DE0			1805+	DC	A(T34)	address of test	
00002350	00001E40			1806+	DC	A(T35)	address of test	
00002354	00001EA0			1807+	DC	A(T36)	address of test	
00002358	00001F00			1808+	DC	A(T37)	address of test	

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT				
					1825	*****			
					1826	*	Register equates		
					1827	*****			
			00000000	00000001	1829	R0	EQU	0	
			00000001	00000001	1830	R1	EQU	1	
			00000002	00000001	1831	R2	EQU	2	
			00000003	00000001	1832	R3	EQU	3	
			00000004	00000001	1833	R4	EQU	4	
			00000005	00000001	1834	R5	EQU	5	
			00000006	00000001	1835	R6	EQU	6	
			00000007	00000001	1836	R7	EQU	7	
			00000008	00000001	1837	R8	EQU	8	
			00000009	00000001	1838	R9	EQU	9	
			0000000A	00000001	1839	R10	EQU	10	
			0000000B	00000001	1840	R11	EQU	11	
			0000000C	00000001	1841	R12	EQU	12	
			0000000D	00000001	1842	R13	EQU	13	
			0000000E	00000001	1843	R14	EQU	14	
			0000000F	00000001	1844	R15	EQU	15	
					1846	*****			
					1847	*	Register equates		
					1848	*****			
			00000000	00000001	1850	V0	EQU	0	
			00000001	00000001	1851	V1	EQU	1	
			00000002	00000001	1852	V2	EQU	2	
			00000003	00000001	1853	V3	EQU	3	
			00000004	00000001	1854	V4	EQU	4	
			00000005	00000001	1855	V5	EQU	5	
			00000006	00000001	1856	V6	EQU	6	
			00000007	00000001	1857	V7	EQU	7	
			00000008	00000001	1858	V8	EQU	8	
			00000009	00000001	1859	V9	EQU	9	
			0000000A	00000001	1860	V10	EQU	10	
			0000000B	00000001	1861	V11	EQU	11	
			0000000C	00000001	1862	V12	EQU	12	
			0000000D	00000001	1863	V13	EQU	13	
			0000000E	00000001	1864	V14	EQU	14	
			0000000F	00000001	1865	V15	EQU	15	
			00000010	00000001	1866	V16	EQU	16	
			00000011	00000001	1867	V17	EQU	17	
			00000012	00000001	1868	V18	EQU	18	
			00000013	00000001	1869	V19	EQU	19	
			00000014	00000001	1870	V20	EQU	20	
			00000015	00000001	1871	V21	EQU	21	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES														
BEGIN	I	00000200	2	93	59	90	91												
CC	U	00000008	1	413	168														
CCFOUND	X	000010DC	1	385	155	175													
CCMASK	U	00000009	1	414	126														
CCMSG	U	00000268	1	144	138														
CCPRTEXP	C	00001086	1	365	172														
CCPRTGOT	C	00001096	1	368	179														
CCPRTLNE	C	00001043	16	360	370	182													
CCPRTLNG	U	00000055	1	370	181														
CCPRTNAME	C	00001070	8	363	165														
CCPRTNUM	C	00001053	3	361	163														
CCPSW	F	000010D4	4	384	152	545	571	597	623	649	677	703	729	755	781	809	835		
					861	887	913	939	967	993	1019	1045	1071	1097	1134	1160	1187		
					1213	1240	1266	1293	1319	1360	1386	1413	1439	1466	1492	1519	1545		
					1572	1598	1625	1651	1678	1704	1731	1757							
CTLRO	F	0000047C	4	307	103	104	105	106											
DECNUM	C	000010C4	16	380	160	162	169	171	176	178	194	196	203	205					
E6TADR	A	00000484	4	310	112														
E6TEST	4	00000000	28	408	121														
E6TESTS	F	000022C8	4	1769	310														
EDIT	X	00001098	18	375	161	170	177	195	204										
ENDTEST	U	00000352	1	225	117														
EOJ	I	00000460	4	297	228														
EOJPSW	D	00000450	8	295	297														
FAILCONT	U	00000342	1	215	185														
FAILED	F	00001000	4	337	217	226													
FAILMSG	U	000002F8	1	192	133														
FAILPSW	D	00000468	8	299	301														
FAILTEST	I	00000478	4	301	229														
IMAGE	1	00000000	9104	0															
K	U	00000400	1	320	321	322	323												
K64	U	00010000	1	322															
MB	U	00000007	1	412	146	202													
MB	U	00100000	1	323															
MSG	I	00000398	4	261	244														
MSGCMD	C	000003E2	9	287	274	275													
MSGMSG	C	000003EB	95	288	268	285	266												
MSGMVC	I	000003DC	6	285	272														
MSGOK	I	000003AE	2	270	267														
MSGRET	I	000003C8	4	281	278														
MSGSAVE	F	000003D0	4	284	264	281													
NEXTE6	U	0000022A	1	114	136	220													
OPNAME	C	0000000A	8	416	165	199													
PAGE	U	00001000	1	321															
PRT3	C	000010AE	18	378	161	162	163	170	171	172	177	178	179	195	196	197	204		
PRTLNE	C	00001004	16	345	205	206	209												
					352	208													
					206														
					206														
PRTLNG	U	0000003F	1	352	208														
PRTM3	C	00001040	2	350	206														
PRTNAME	C	0000102F	8	348	199														
PRTNUM	C	00001014	3	346	197														
R0	U	00000000	1	1829	53	103	106	119	181	208	216	217	243	245	261	264	266		
					268	270	281	544	570	596	622	648	676	702	728	754	780		
					808	834	860	886	912	938	966	992	1018	1044	1070	1096	1133		
					1159	1186	1212	1239	1265	1292	1318	1359	1385	1412	1438	1465	1491		
					1518	1544	1571	1597	1624	1650	1677	1703	1730	1756					

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE28	F	00001BE0	4	1268	1258 1262
RE29	F	00001C40	4	1295	1285 1289
RE3	F	00001280	4	599	589 593
RE30	F	00001CA0	4	1321	1311 1315
RE31	F	00001D00	4	1362	1352 1356
RE32	F	00001D60	4	1388	1378 1382
RE33	F	00001DC0	4	1415	1405 1409
RE34	F	00001E20	4	1441	1431 1435
RE35	F	00001E80	4	1468	1458 1462
RE36	F	00001EE0	4	1494	1484 1488
RE37	F	00001F40	4	1521	1511 1515
RE38	F	00001FA0	4	1547	1537 1541
RE39	F	00002000	4	1574	1564 1568
RE4	F	000012E0	4	625	615 619
RE40	F	00002060	4	1600	1590 1594
RE41	F	000020C0	4	1627	1617 1621
RE42	F	00002120	4	1653	1643 1647
RE43	F	00002180	4	1680	1670 1674
RE44	F	000021E0	4	1706	1696 1700
RE45	F	00002240	4	1733	1723 1727
RE46	F	000022A0	4	1759	1749 1753
RE5	F	00001340	4	651	641 645
RE6	F	000013A0	4	679	669 673
RE7	F	00001400	4	705	695 699
RE8	F	00001460	4	731	721 725
RE9	F	000014C0	4	757	747 751
REA1	A	00001198	4	537	
REA10	A	000014F8	4	773	
REA11	A	00001558	4	801	
REA12	A	000015B8	4	827	
REA13	A	00001618	4	853	
REA14	A	00001678	4	879	
REA15	A	000016D8	4	905	
REA16	A	00001738	4	931	
REA17	A	00001798	4	959	
REA18	A	000017F8	4	985	
REA19	A	00001858	4	1011	
REA2	A	000011F8	4	563	
REA20	A	000018B8	4	1037	
REA21	A	00001918	4	1063	
REA22	A	00001978	4	1089	
REA23	A	000019D8	4	1126	
REA24	A	00001A38	4	1152	
REA25	A	00001A98	4	1179	
REA26	A	00001AF8	4	1205	
REA27	A	00001B58	4	1232	
REA28	A	00001BB8	4	1258	
REA29	A	00001C18	4	1285	
REA3	A	00001258	4	589	
REA30	A	00001C78	4	1311	
REA31	A	00001CD8	4	1352	
REA32	A	00001D38	4	1378	
REA33	A	00001D98	4	1405	
REA34	A	00001DF8	4	1431	
REA35	A	00001E58	4	1458	
REA36	A	00001EB8	4	1484	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES		
REA37	A	00001F18	4	1511			
REA38	A	00001F78	4	1537			
REA39	A	00001FD8	4	1564			
REA4	A	000012B8	4	615			
REA40	A	00002038	4	1590			
REA41	A	00002098	4	1617			
REA42	A	000020F8	4	1643			
REA43	A	00002158	4	1670			
REA44	A	000021B8	4	1696			
REA45	A	00002218	4	1723			
REA46	A	00002278	4	1749			
REA5	A	00001318	4	641			
REA6	A	00001378	4	669			
REA7	A	000013D8	4	695			
REA8	A	00001438	4	721			
REA9	A	00001498	4	747			
READDR	A	00000018	4	419	131		
REG2LOW	U	000000DD	1	327			
REG2PATT	U	AABBCCDD	1	326			
RELEN	A	00000014	4	418			
RPTDWSAV	D	00000388	8	254	243	245	
RPTERROR	I	00000360	4	238	183	210	
RPTSAVE	F	00000380	4	251	238	248	
RPTSVR5	F	00000384	4	252	239	247	
SVOLDPSW	U	00000140	0	55			
T1	A	00001180	4	529	1772		
T10	A	000014E0	4	765	1781		
T11	A	00001540	4	793	1782		
T12	A	000015A0	4	819	1783		
T13	A	00001600	4	845	1784		
T14	A	00001660	4	871	1785		
T15	A	000016C0	4	897	1786		
T16	A	00001720	4	923	1787		
T17	A	00001780	4	951	1788		
T18	A	000017E0	4	977	1789		
T19	A	00001840	4	1003	1790		
T2	A	000011E0	4	555	1773		
T20	A	000018A0	4	1029	1791		
T21	A	00001900	4	1055	1792		
T22	A	00001960	4	1081	1793		
T23	A	000019C0	4	1118	1794		
T24	A	00001A20	4	1144	1795		
T25	A	00001A80	4	1171	1796		
T26	A	00001AE0	4	1197	1797		
T27	A	00001B40	4	1224	1798		
T28	A	00001BA0	4	1250	1799		
T29	A	00001C00	4	1277	1800		
T3	A	00001240	4	581	1774		
T30	A	00001C60	4	1303	1801		
T31	A	00001CC0	4	1344	1802		
T32	A	00001D20	4	1370	1803		
T33	A	00001D80	4	1397	1804		
T34	A	00001DE0	4	1423	1805		
T35	A	00001E40	4	1450	1806		
T36	A	00001EA0	4	1476	1807		
T37	A	00001F00	4	1503	1808		

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES												
T38	A	00001F60	4	1529	1809												
T39	A	00001FC0	4	1556	1810												
T4	A	000012A0	4	607	1775												
T40	A	00002020	4	1582	1811												
T41	A	00002080	4	1609	1812												
T42	A	000020E0	4	1635	1813												
T43	A	00002140	4	1662	1814												
T44	A	000021A0	4	1688	1815												
T45	A	00002200	4	1715	1816												
T46	A	00002260	4	1741	1817												
T5	A	00001300	4	633	1776												
T6	A	00001360	4	661	1777												
T7	A	000013C0	4	687	1778												
T8	A	00001420	4	713	1779												
T9	A	00001480	4	739	1780												
TESTCC	I	00000264	4	138	128												
TESTREST	U	0000024C	1	130	148												
TNUM	H	00000004	2	410	159	193											
TSUB	A	00000000	4	409	123												
TTABLE	F	000022C8	4	1771													
V0	U	00000000	1	1850													
V1	U	00000001	1	1851	540	542	543	566	568	569	592	594	595	618	620	621	644
					646	647	672	674	675	698	700	701	724	726	727	750	752
					753	776	778	779	804	806	807	830	832	833	856	858	859
					882	884	885	908	910	911	934	936	937	962	964	965	988
					990	991	1014	1016	1017	1040	1042	1043	1066	1068	1069	1092	1094
					1095	1129	1131	1132	1155	1157	1158	1182	1184	1185	1208	1210	1211
					1235	1237	1238	1261	1263	1264	1288	1290	1291	1314	1316	1317	1355
					1357	1358	1381	1383	1384	1408	1410	1411	1434	1436	1437	1461	1463
					1464	1487	1489	1490	1514	1516	1517	1540	1542	1543	1567	1569	1570
					1593	1595	1596	1620	1622	1623	1646	1648	1649	1673	1675	1676	1699
					1701	1702	1726	1728	1729	1752	1754	1755					
V10	U	0000000A	1	1860													
V11	U	0000000B	1	1861													
V12	U	0000000C	1	1862													
V13	U	0000000D	1	1863													
V14	U	0000000E	1	1864													
V15	U	0000000F	1	1865													
V16	U	00000010	1	1866													
V17	U	00000011	1	1867													
V18	U	00000012	1	1868													
V19	U	00000013	1	1869													
V1FUDGE	X	00001130	16	397	540	566	592	618	644	672	698	724	750	776	804	830	856
					882	908	934	962	988	1014	1040	1066	1092	1129	1155	1182	1208
					1235	1261	1288	1314	1355	1381	1408	1434	1461	1487	1514	1540	1567
					1593	1620	1646	1673	1699	1726	1752						
V1FUDGE	X	00001140	16	398													
V1INPUT	C	00001150	16	399													
V10UTPUT	X	000010F8	16	393	132	543	569	595	621	647	675	701	727	753	779	807	833
					859	885	911	937	965	991	1017	1043	1069	1095	1132	1158	1185
					1211	1238	1264	1291	1317	1358	1384	1411	1437	1464	1490	1517	1543
					1570	1596	1623	1649	1676	1702	1729	1755					
V2	U	00000002	1	1852	541	542	567	568	593	594	619	620	645	646	673	674	699
					700	725	726	751	752	777	778	805	806	831	832	857	858
					883	884	909	910	935	936	963	964	989	990	1015	1016	1041
					1042	1067	1068	1093	1094	1130	1131	1156	1157	1183	1184	1209	1210

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	9104	0000- 238F	0000- 238F
Regi on		9104	0000- 238F	0000- 238F
CSECT	ZVE6TST	9104	0000- 238F	0000- 238F

STMT	FILE NAME
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1	/devstor/dev/tests/zvector-e6-12-countzonedhighlow.asm
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** NO ERRORS FOUND **